

# 1.6-MHz Synchronous Switch-Mode Li-Ion and Li-Polymer Stand-Alone Battery Charger with Integrated MOSFETs and Power Path Selector

Check for Samples: [bq24170](#), [bq24172](#)

## FEATURES

- **1.6MHz Synchronous Switch-Mode Charger with 4A Integrated N-MOSFETs**
- **Up to 94% Efficiency**
- **30V Input Rating with Adjustable Over-Voltage Protection**
  - 4.5V to 17V Input Operating Voltage Range
- **Battery Charge Voltage**
  - bq24170: 1, 2, or 3-Cell with 4.2V/Cell
  - bq24172: Adjustable Charge Voltage
- **High Integration**
  - **Automatic Power Path Selector Between Adapter and Battery**
  - **Dynamic Power Management**
  - **Integrated 20-V Switching MOSFETs**
  - **Integrated Bootstrap Diode**
  - **Internal Loop Compensation**
  - **Internal Digital Soft Start**
- **Safety**
  - **Thermal Regulation Loop Throttles Back Current to Limit  $T_j = 120^\circ\text{C}$**
  - **Thermal Shutdown**
  - **Battery Thermistor Sense Hot/Cold Charge Suspend & Battery Detect**
  - **Input Over-Voltage Protection with Programmable Threshold**
  - **Cycle-by-Cycle Current Limit**
- **Accuracy**
  - **$\pm 0.5\%$  Charge Voltage Regulation**
  - **$\pm 4\%$  Charge Current Regulation**
  - **$\pm 4\%$  Input Current Regulation**
- **Less than 15 $\mu\text{A}$  Battery Current with Adapter Removed**
- **Less than 1.5mA Input Current with Adapter Present and Charge Disabled**
- **Small QFN Package**
  - 3.5mm  $\times$  5.5mm QFN-24 Pin

## APPLICATIONS

- **Tablet PC**
- **Netbook and Ultra-Mobile Computers**
- **Portable Data Capture Terminals**
- **Portable Printers**
- **Medical Diagnostics Equipment**
- **Battery Bay Chargers**
- **Battery Back-Up Systems**

## DESCRIPTION

The bq24170/172 is highly integrated stand-alone Li-ion and Li-polymer switch-mode battery charger with two integrated N-channel power MOSFETs. It offers a constant-frequency synchronous PWM controller with high accuracy regulation of input current, charge current, and voltage. It closely monitors the battery pack temperature to allow charge only in a preset temperature window. It also provides battery detection, pre-conditioning, charge termination, and charge status monitoring. The thermal regulation loop reduces charge current to maintain the junction temperature of 120°C during operation.

The bq24170/172 charges the battery in three phases: preconditioning, constant current, and constant voltage. The bq24170 charges one, two, or three cells (selected by CELL pin), and the bq24172 is adjustable for up to three series Li+ cells.

Charge is terminated when the current reaches 10% of the fast charge rate. A programmable charge timer offers a safety back up. The bq24170/172 automatically restarts the charge cycle if the battery voltage falls below an internal threshold, and enters a low-quiescent current sleep mode when the input voltage falls below the battery voltage.

The bq24170/172 features Dynamic Power Management (DPM) to reduce the charge current when the input power limit is reached to avoid over-loading the adapter. A highly-accurate current-sense amplifier enables precise measurement of input current from adapter to monitor overall system power.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

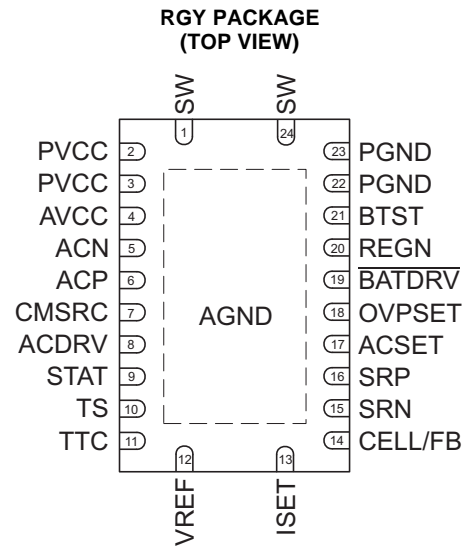
## DESCRIPTION (CONTINUED)

The bq24170/172 provides power path selector gate driver ACDRV/CMSRC on input NMOS pair ACFET (Q1) and RBFET (Q2), and BATDRV on a battery PMOS device (Q3). When the qualified adapter is present, the system is directly connected to the adapter. Otherwise, the system is connected to the battery. In addition, the power path prevents battery from boosting back to the input.

The bq24170/172 charges a battery from a DC source as high as 17V, including a car battery. The input over-voltage limit is adjustable through the OVPSET pin. The AVCC, ACP, and ACN pins have a 30V rating. When a high voltage DC source is inserted, Q1/Q2 remain off to avoid high voltage damage to the system.

For 1 cell applications, if the battery is not removable, the system can be directly connected to the battery to simplify the power path design and lower the cost. With this configuration, the battery can automatically supplement the system load if the adapter is overloaded.

The bq24170/172 is available in a 24-pin, 3.5mm x 5.5mm thin QFN package.



## PIN FUNCTIONS

PIN		TYPE	DESCRIPTION
NO.	NAME		
1,24	SW	P	Switching node, charge current output inductor connection. Connect the 0.047- $\mu$ F bootstrap capacitor from SW to BTST.
2,3	PVCC	P	Charger input voltage. Connect at least 10- $\mu$ F ceramic capacitor from PVCC to PGND and place it as close as possible to IC.
4	AVCC	P	IC power positive supply. Place a 1- $\mu$ F ceramic capacitor from AVCC to AGND and place it as close as possible to IC. Place a 10- $\Omega$ resistor from input side to AVCC pin to filter the noise. For 5V input, a 5- $\Omega$ resistor is recommended.
5	ACN	I	Adapter current sense resistor negative input. A 0.1- $\mu$ F ceramic capacitor is placed from ACN to ACP to provide differential-mode filtering. An optional 0.1- $\mu$ F ceramic capacitor is placed from ACN pin to AGND for common-mode filtering.
6	ACP	P/I	Adapter current sense resistor positive input. A 0.1- $\mu$ F ceramic capacitor is placed from ACN to ACP to provide differential-mode filtering. A 0.1- $\mu$ F ceramic capacitor is placed from ACP pin to AGND for common-mode filtering.
7	CMSRC	O	Connect to common source of N-channel ACFET and reverse blocking MOSFET (RBFET). Place 4-k $\Omega$ resistor from CMSRC pin to the common source of ACFET and RBFET to control the turn-on speed. The resistance between ACDRV and CMSRC should be 500-k $\Omega$ or bigger.
8	ACDRV	O	AC adapter to system switch driver output. Connect to 4-k $\Omega$ resistor then to the gate of the ACFET N-channel power MOSFET and the reverse conduction blocking N-channel power MOSFET. Connect both FETs as common-source. The internal gate drive is asymmetrical, allowing a quick turn-off and slower turn-on in addition to the internal break-before-make logic with respect to the BATDRV.
9	STAT	O	Open-drain charge status pin with 10-k $\Omega$ pull up to power rail. The STAT pin can be used to drive LED or communicate with the host processor. It indicates various charger operations: LOW when charge in progress. HIGH when charge is complete or in SLEEP mode. Blinking at 0.5Hz when fault occurs, including charge suspend, input over-voltage, timer fault and battery absent.
10	TS	I	Temperature qualification voltage input. Connect a negative temperature coefficient thermistor. Program the hot and cold temperature window with a resistor divider from VREF to TS to AGND. The temperature qualification window can be set to 5-40°C or wider. The 103AT thermistor is recommended.

**PIN FUNCTIONS (continued)**

PIN		TYPE	DESCRIPTION
NO.	NAME		
11	TTC	I	Safety Timer and termination control. Connect a capacitor from this node to AGND to set the fast charge safety timer(5.6min/nF). Pre-charge timer is internally fixed to 30 minutes. Pull the TTC to LOW to disable the charge termination and safety timer. Pull the TTC to HIGH to disable the safety timer but allow the charge termination.
12	VREF	P	3.3V reference voltage output. Place a 1-μF ceramic capacitor from VREF to AGND pin close to the IC. This voltage could be used for programming ISET and ACSET and TS pins. It may also serve as the pull-up rail of STAT pin and CELL pin.
13	ISET	I	Fast charge current set point. Use a voltage divider from VREF to ISET to AGND to set the fast charge current:  $I_{CHG} = \frac{V_{ISET}}{20 \times R_{SR}}$ <p>The pre-charge and termination current is internally as one tenth of the charge current. The charger is disabled when ISET pin voltage is below 40mV and enabled when ISET pin voltage is above 120mV.</p>
14	CELL (bq24170)	I	Cell selection pin. Set CELL pin LOW for 1-cell, Float for 2-cell (0.8V-1.8V), and HIGH for 3-cell with a fixed 4.2V per cell.
	FB (bq24172)		Charge voltage analog feedback adjustment. Connect the output of a resistor divider powered from the battery terminals to VFB to AGND. Output voltage is regulated to 2.1V on FB pin during constant-voltage mode.
15	SRN	I	Charge current sense resistor negative input. A 0.1-μF ceramic capacitor is placed from SRN to SRP to provide differential-mode filtering. A 0.1-μF ceramic capacitor is placed from SRN pin to AGND for common-mode filtering.
16	SRP	I/P	Charge current sense resistor, positive input. A 0.1-μF ceramic capacitor is placed from SRN to SRP to provide differential-mode filtering. A 0.1-μF ceramic capacitor is placed from SRP pin to AGND for common-mode filtering.
17	ACSET	I	Input current set point. Use a voltage divider from VREF to ACSET to AGND to set this value:  $I_{DPM} = \frac{V_{ACSET}}{20 \times R_{AC}}$
18	OVPSET	I	Valid input voltage set point. Use a voltage divider from input to OVPSET to AGND to set this voltage. The voltage above internal 1.6V reference indicates input over-voltage, and the voltage below internal 0.5V reference indicates input under-voltage. In either condition, charge terminates, and input NMOS pair ACFET/RBFET turn off. LED driven by STAT pin keeps blinking, reporting fault condition.
19	BATDRV	O	Battery discharge MOSFET gate driver output. Connect to 1kohm resistor to the gate of the BATFET P-channel power MOSFET. Connect the source of the BATFET to the system load voltage node. Connect the drain of the BATFET to the battery pack positive node. The internal gate drive is asymmetrical to allow a quick turn-off and slower turn-on, in addition to the internal break-before-make logic with respect to ACDRV.
20	REGN	P	PWM low side driver positive 6V supply output. Connect a 1-μF ceramic capacitor from REGN to PGND pin, close to the IC. Generate high-side driver bootstrap voltage by integrated diode from REGN to BTST.
21	BTST	P	PWM high side driver positive supply. Connect the 0.047-μF bootstrap capacitor from SW to BTST.
22,23	PGND	P	Power ground. Ground connection for high-current power converter node. On PCB layout, connect directly to ground connection of input and output capacitors of the charger. Only connect to AGND through the Thermal Pad underneath the IC.
Thermal Pad	AGND	P	Exposed pad beneath the IC. Always solder Thermal Pad to the board, and have vias on the Thermal Pad plane star-connecting to AGND and ground plane for high-current power converter. It dissipates the heat from the IC.

TYPICAL APPLICATIONS

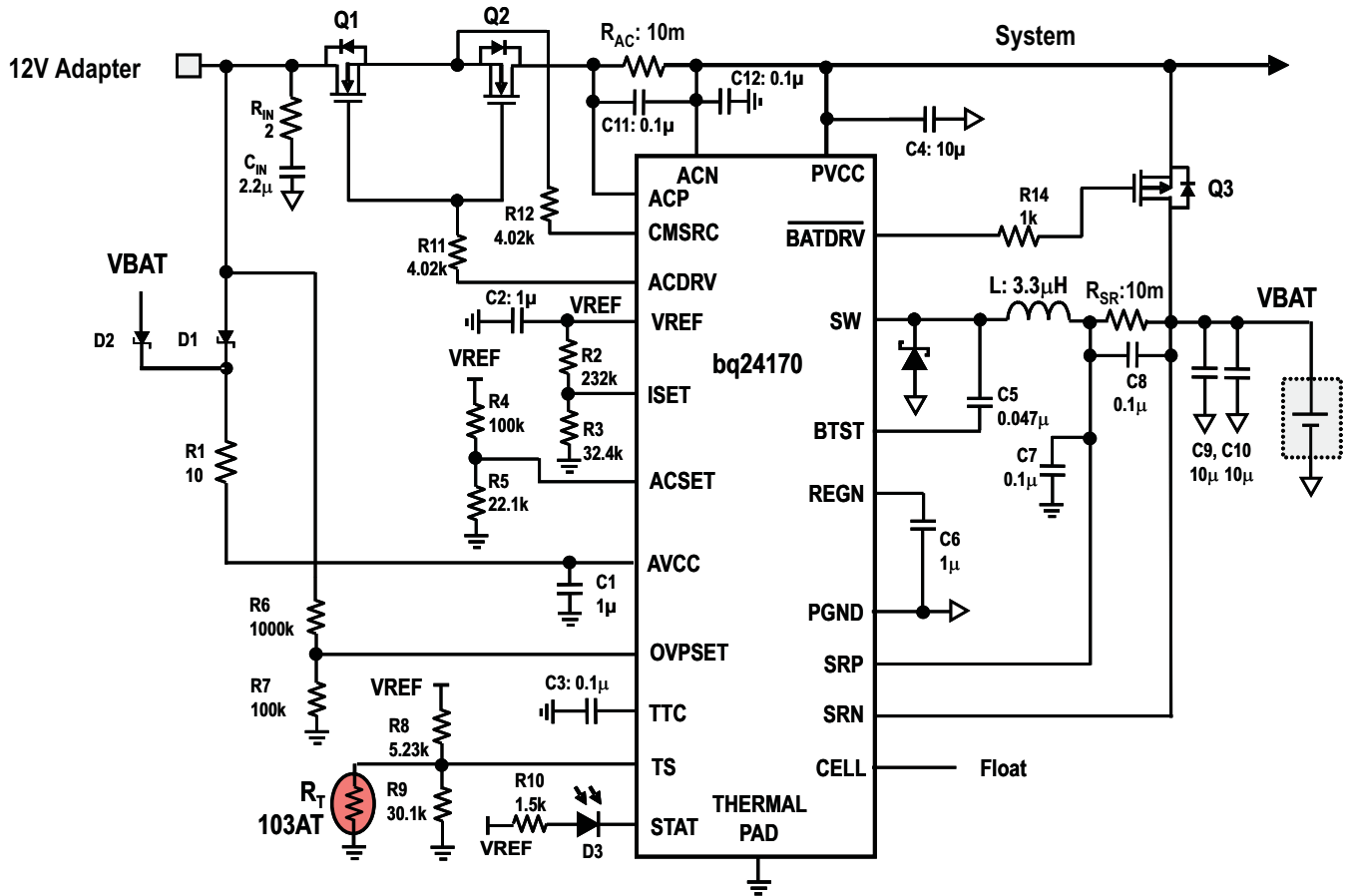


Figure 1. Typical Application Schematic (12V input, 2 cell battery 8.4V, 2A charge current, 0.2A pre-charge/termination current, 3A DPM current, 18V input OVP, 0 – 45°C TS)

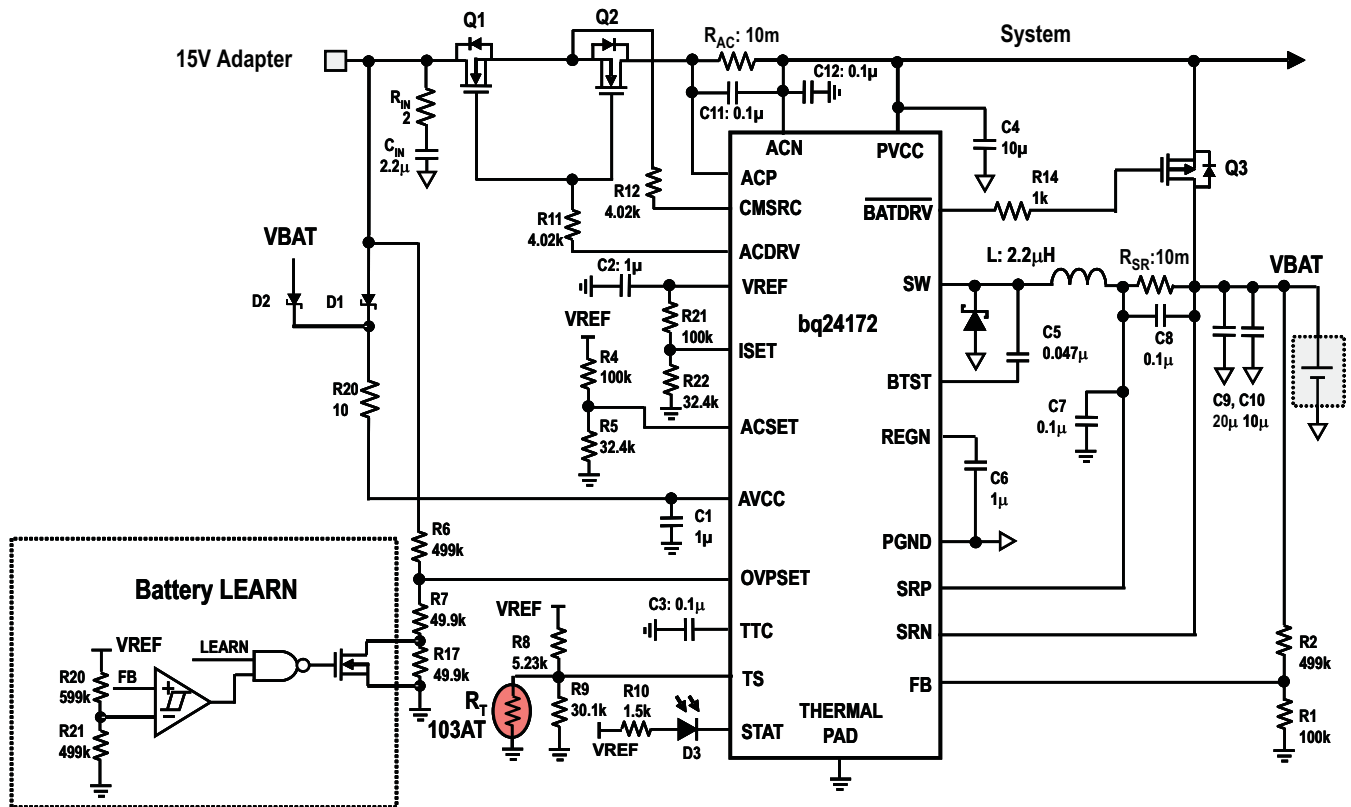


Figure 2. Typical Application Schematic with Battery Learn Function (15V input, 3 cell battery 12.6V, 4A charge current, 0.4A pre-charge/termination current, 4A DPM current, 0 – 45°C TS)

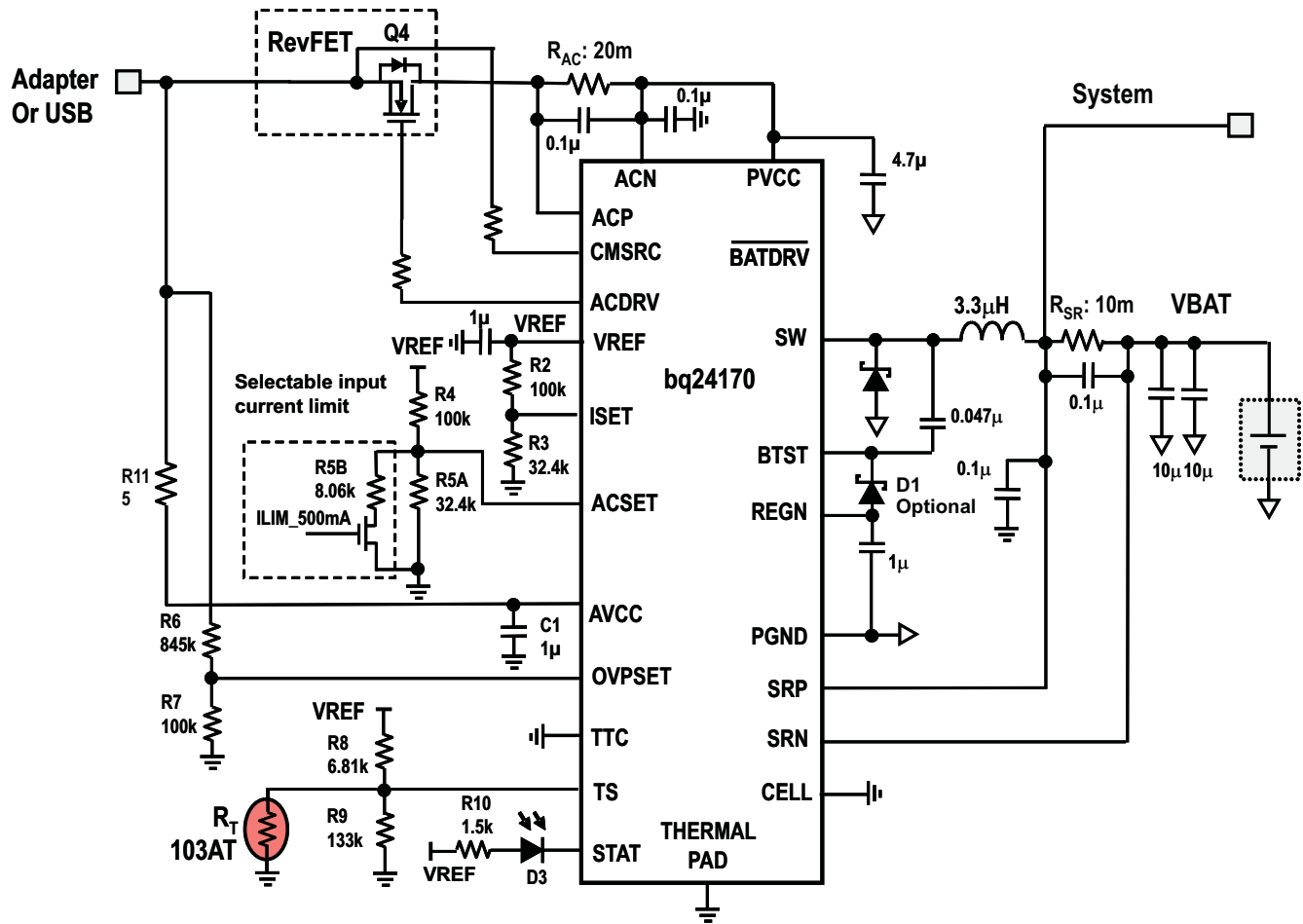


Figure 3. Typical Application Schematic with Single Cell Unremovable Battery (USB or adapter with input OVP 15V, up to 4A charge current, 0.4A pre-charge current, 2A adapter current or 500mA USB current, 5 – 40°C TS, system connected before sense resistor)

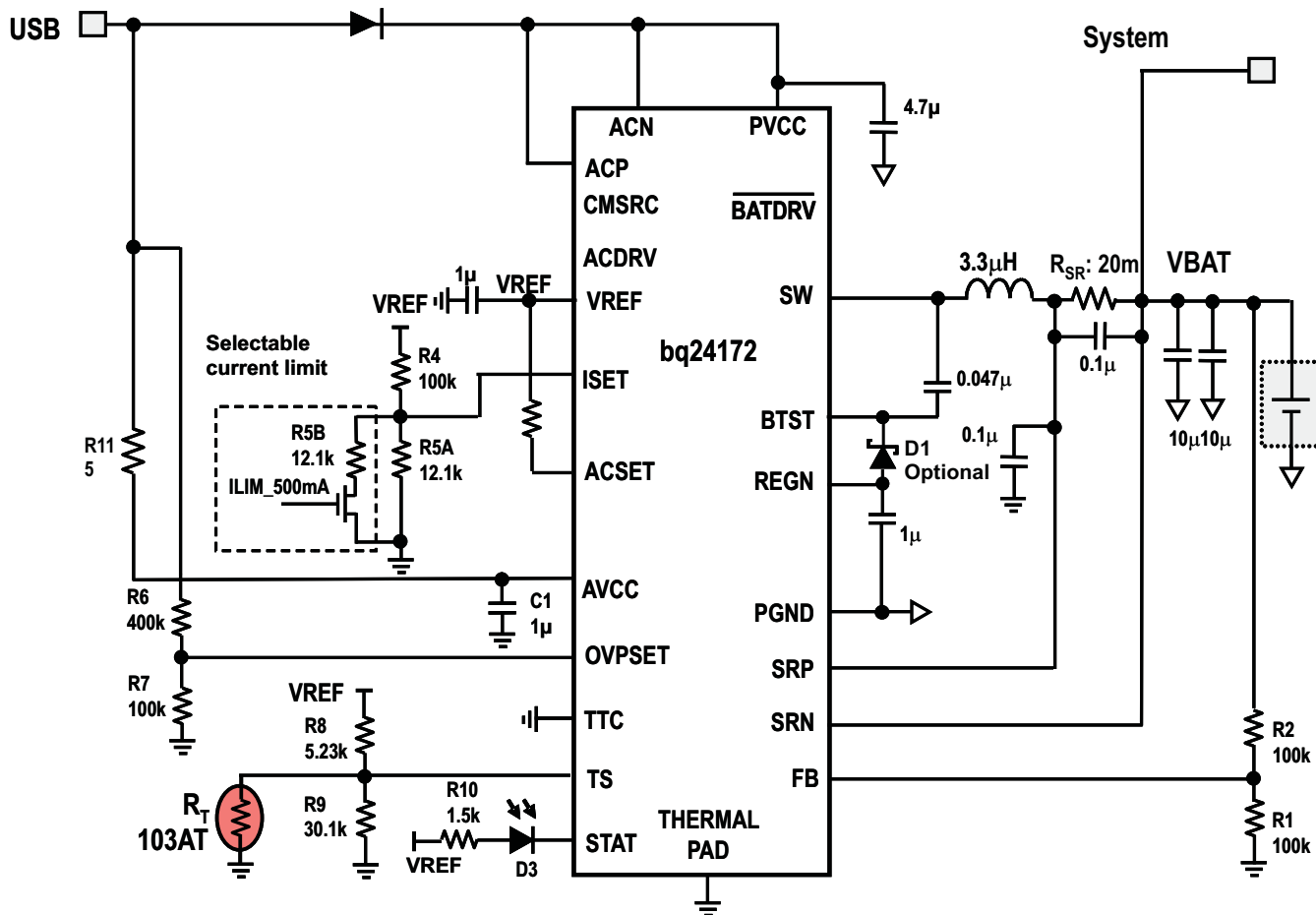


Figure 4. Typical Application Schematic with Single Cell Unremovable Battery (USB with input OVP 8V, selectable charge current limit of 900mA or 500mA, 0 – 45°C TS, system connected after sense resistor)

ORDERING INFORMATION<sup>(1)</sup>

PART NUMBER	PART MARKING	PACKAGE	ORDERING NUMBER	QUANTITY
bq24170	bq24170	24-Pin 3.5mm×5.5mm QFN	bq24170RGYR	3000
			bq24170RGYT	250
bq24172	bq24172	24-Pin 3.5mm×5.5mm QFN	bq24172RGYR	3000
			bq24172RGYT	250

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

## ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) <sup>(1)(2)</sup>

		VALUE	UNIT
Voltage range (with respect to AGND)	PVCC	–0.3 to 20	V
	AVCC, ACP, ACN, ACDRV, CMSRC, STAT	–0.3 to 30	
	BTST	–0.3 to 26	
	BATDRV, SRP, SRN	–0.3 to 20	
	SW	–2 to 20	
	FB (bq24172)	–0.3 to 16	
	OVPSET, REGN, TS, TTC, CELL (bq24170)	–0.3 to 7	
	VREF, ISET, ACSET	–0.3 to 3.6	
	PGND	–0.3 to 0.3	
Maximum difference voltage	SRP–SRN, ACP–ACN	–0.5 to 0.5	V
Junction temperature range, T <sub>J</sub>		–40 to 155	°C
Storage temperature range, T <sub>stg</sub>		–55 to 155	°C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to GND if not specified. Currents are positive into, negative out of the specified terminal. Consult Packaging Section of the data book for thermal limitations and considerations of packages.

## THERMAL INFORMATION

THERMAL METRIC <sup>(1)</sup>		bq24170/2	UNITS
		RGY	
		24 PINS	
θ <sub>JA</sub>	Junction-to-ambient thermal resistance <sup>(2)</sup>	35.7	°C/W
ψ <sub>JT</sub>	Junction-to-top characterization parameter <sup>(3)</sup>	0.4	
ψ <sub>JB</sub>	Junction-to-board characterization parameter <sup>(4)</sup>	31.2	

- (1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-top characterization parameter, ψ<sub>JT</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- (4) The junction-to-board characterization parameter, ψ<sub>JB</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).

## RECOMMENDED OPERATING CONDITIONS

		MIN	MAX	UNIT
Input voltage	V <sub>IN</sub>	4.5	17	V
Output voltage	V <sub>OUT</sub>		13.5	V
Output current (R <sub>SR</sub> 10mΩ)	I <sub>OUT</sub>	0.6	4	A
Maximum difference voltage	ACP - ACN	–200	200	mV
	SRP–SRN	–200	200	mV
Operation free-air temperature range, T <sub>A</sub>		–40	85	°C



## ELECTRICAL CHARACTERISTICS

4.5V ≤ V(PVCC, AVCC) ≤ 17V, −40°C < T<sub>J</sub> + 125°C, typical values are at T<sub>A</sub> = 25°C, with respect to AGND (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>OPERATING CONDITIONS</b>						
V <sub>AVCC_OP</sub>	AVCC input voltage operating range during charging		4.5		17	V
<b>QUIESCENT CURRENTS</b>						
I <sub>BAT</sub>	Battery discharge current (sum of currents into AVCC, PVCC, ACP, ACN)	V <sub>AVCC</sub> > V <sub>UVLO</sub> , V <sub>SRN</sub> > V <sub>AVCC</sub> (SLEEP), T <sub>J</sub> = 0°C to 85°C			15	μA
		BTST, SW, SRP, SRN, V <sub>AVCC</sub> > V <sub>UVLO</sub> , V <sub>AVCC</sub> > V <sub>SRN</sub> , ISET < 40mV, V <sub>BAT</sub> =12.6V, Charge disabled			25	
		BTST, SW, SRP, SRN, V <sub>AVCC</sub> > V <sub>UVLO</sub> , V <sub>AVCC</sub> > V <sub>SRN</sub> , ISET > 120mV, V <sub>BAT</sub> =12.6V, Charge done			25	
I <sub>AC</sub>	Adapter supply current (sum of current into AVCC, ACP, ACN)	V <sub>AVCC</sub> > V <sub>UVLO</sub> , V <sub>AVCC</sub> > V <sub>SRN</sub> , ISET < 40mV, V <sub>BAT</sub> =12.6V, Charge disabled		1.2	1.5	mA
		V <sub>AVCC</sub> > V <sub>UVLO</sub> , V <sub>AVCC</sub> > V <sub>SRN</sub> , ISET > 120mV, Charge enabled, no switching		2.5	5	
		V <sub>AVCC</sub> > V <sub>UVLO</sub> , V <sub>AVCC</sub> > V <sub>SRN</sub> , ISET > 120mV, Charge enabled, switching		15 <sup>(1)</sup>		
<b>CHARGE VOLTAGE REGULATION</b>						
V <sub>BAT_REG</sub>	SRN regulation voltage (bq24170)	CELL to AGND, 1 cell, measured on SRN		4.2		V
		CELL floating, 2 cells, measured on SRN		8.4		V
		CELL to VREF, 3 cells, measured on SRN		12.6		V
V <sub>FB_REG</sub>	Feedback regulation voltage (bq24172)	Measured on FB		2.1		V
	Charge voltage regulation accuracy	T <sub>J</sub> = 0°C to 85°C	−0.5%		0.5%	
		T <sub>J</sub> = −40°C to 125°C	−0.7%		0.7%	
I <sub>FB</sub>	Leakage current into FB pin (bq24172)	V <sub>FB</sub> = 2.1 V			100	nA
<b>CURRENT REGULATION – FAST CHARGE</b>						
V <sub>ISET</sub>	ISET Voltage Range	R <sub>SENSE</sub> = 10mΩ	0.12		0.8	V
K <sub>ISET</sub>	Charge Current Set Factor (Amps of Charge Current per Volt on ISET pin)	R <sub>SENSE</sub> = 10mΩ		5		A/V
	Charge Current Regulation Accuracy (with Schottky diode on SW)	V <sub>SRP-SRN</sub> = 40 mV	−4%		4%	
		V <sub>SRP-SRN</sub> = 20 mV	−7%		7%	
		V <sub>SRP-SRN</sub> = 5 mV	−25%		25%	
V <sub>ISET_CD</sub>	Charge Disable Threshold	ISET falling	40	50		mV
V <sub>ISET_CE</sub>	Charge Enable Threshold	ISET rising		100	120	mV
I <sub>ISET</sub>	Leakage Current into ISET	V <sub>ISET</sub> = 2V			100	nA
<b>INPUT CURRENT REGULATION</b>						
K <sub>DPM</sub>	Input DPM Current Set Factor (Amps of Input Current per Volt on ACSET)	R <sub>SENSE</sub> = 10mΩ		5		A/V
	Input DPM Current Regulation Accuracy (with Schottky diode on SW)	V <sub>ACP-ACN</sub> = 80 mV	−4%		4%	
		V <sub>ACP-ACN</sub> = 40 mV	−9%		9%	
		V <sub>ACP-ACN</sub> = 20 mV	−15%		15%	
		V <sub>ACP-ACN</sub> = 5 mV	−20%		20%	
		V <sub>ACP-ACN</sub> = 2.5 mV	−40%		40%	
I <sub>ACSET</sub>	Leakage Current into ACSET pin	V <sub>ACSET</sub> = 2V			100	nA
<b>CURRENT REGULATION – PRE-CHARGE</b>						
K <sub>IPRECHG</sub>	Precharge current set factor	Percentage of fast charge current		10% <sup>(2)</sup>		
	Precharge current regulation accuracy	V <sub>SRP-SRN</sub> = 4 mV	−25%		25%	
		V <sub>SRP-SRN</sub> = 2 mV	−40%		40%	

(1) Specified by design

(2) The minimum current is 120 mA on 10mΩ sense resistor.

## ELECTRICAL CHARACTERISTICS (continued)

4.5V ≤ V(PVCC, AVCC) ≤ 17V, −40°C < T<sub>J</sub> + 125°C, typical values are at T<sub>A</sub> = 25°C, with respect to AGND (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>CHARGE TERMINATION</b>						
K <sub>TERM</sub>	Termination current set factor	Percentage of fast charge current		10% <sup>(3)</sup>		
	Termination current regulation accuracy	V <sub>SRP-SRN</sub> = 4 mV	−25%		25%	
		V <sub>SRP-SRN</sub> = 2 mV	−40%		40%	
t <sub>TERM_DEG</sub>	Deglintch time for termination (both edges)			100		ms
t <sub>QUAL</sub>	Termination qualification time	V <sub>SRN</sub> > V <sub>RECH</sub> and I <sub>CHG</sub> < I <sub>TERM</sub>		250		ms
I <sub>QUAL</sub>	Termination qualification current	Discharge current once termination is detected		2		mA
<b>INPUT UNDER-VOLTAGE LOCK-OUT COMPARATOR (UVLO)</b>						
V <sub>UVLO</sub>	AC under-voltage rising threshold	Measure on AVCC	3.4	3.6	3.8	V
V <sub>UVLO_HYS</sub>	AC under-voltage hysteresis, falling	Measure on AVCC		300		mV
<b>SLEEP COMPARATOR (REVERSE DISCHARGING PROTECTION)</b>						
V <sub>SLEEP</sub>	SLEEP mode threshold	V <sub>AVCC</sub> − V <sub>SRN</sub> falling	50	90	150	mV
V <sub>SLEEP_HYS</sub>	SLEEP mode hysteresis	V <sub>AVCC</sub> − V <sub>SRN</sub> rising		200		mV
t <sub>SLEEP_FALL_CD</sub>	SLEEP deglitch to disable charge	V <sub>AVCC</sub> − V <sub>SRN</sub> falling		1		ms
t <sub>SLEEP_FALL_FETOFF</sub>	SLEEP deglitch to turn off input FETs	V <sub>AVCC</sub> − V <sub>SRN</sub> falling		5		ms
t <sub>SLEEP_FALL</sub>	Deglitch to enter SLEEP mode, disable VREF and enter low quiescent mode	V <sub>AVCC</sub> − V <sub>SRN</sub> falling		100		ms
t <sub>SLEEP_PWRUP</sub>	Deglitch to exit SLEEP mode, and enable VREF	V <sub>AVCC</sub> − V <sub>SRN</sub> rising		30		ms
<b>ACN-SRN COMPARATOR</b>						
V <sub>ACN-SRN</sub>	Threshold to turn on BATFET	V <sub>ACN-SRN</sub> falling	150	220	300	mV
V <sub>ACN-SRN_HYS</sub>	Hysteresis to turn off BATFET	V <sub>ACN-SRN</sub> rising		100		mV
t <sub>BATFETOFF_DEG</sub>	Deglitch to turn on BATFET	V <sub>ACN-SRN</sub> falling		2		ms
t <sub>BATFETON_DEG</sub>	Deglitch to turn off BATFET	V <sub>ACN-SRN</sub> rising		50		μs
<b>BAT LOWV COMPARATOR</b>						
V <sub>LOWV</sub>	Precharge to fast charge transition	bq24170, CELL to AGND, 1 cell, measure on SRN	2.87	2.9	2.93	V
		bq24170, CELL floating, 2 cells, measure on SRN	5.74	5.8	5.86	
		bq24170, CELL to VREF, 3 cells, measure on SRN	8.61	8.7	8.79	
		bq24172, measure on FB	1.43	1.45	1.47	
V <sub>LOWV_HYS</sub>	Fast charge to precharge hysteresis	bq24170, CELL to AGND, 1 cell, measure on SRN		200		mV
		bq24170, CELL floating, 2 cells, measure on SRN		400		
		bq24170, CELL to VREF, 3 cells, measure on SRN		600		
		bq24172, measure on FB		100		
t <sub>pre2fas</sub>	V <sub>LOWV</sub> rising deglitch	Delay to start fast charge current		25		ms
t <sub>fast2pre</sub>	V <sub>LOWV</sub> falling deglitch	Delay to start precharge current		25		ms
<b>RECHARGE COMPARATOR</b>						
V <sub>RECHG</sub>	Recharge Threshold, below regulation voltage limit, V <sub>BAT_REG</sub> − V <sub>SRN</sub> (bq24170), or V <sub>FB_REG</sub> − V <sub>FB</sub> (bq24172)	bq24170, CELL to AGND, 1 cell, measure on SRN	70	100	130	mV
		bq24170, CELL floating, 2 cells, measure on SRN	140	200	260	
		bq24170, CELL to VREF, 3 cells, measure on SRN	210	300	390	
		bq24172, measure on FB	35	50	65	
t <sub>RECH_RISE_DEG</sub>	V <sub>RECHG</sub> rising deglitch	VFB decreasing below V <sub>RECHG</sub>		10		ms
t <sub>RECH_FALL_DEG</sub>	V <sub>RECHG</sub> falling deglitch	VFB increasing above V <sub>RECHG</sub>		10		ms

(3) The minimum current is 120 mA on 10mΩ sense resistor.

## ELECTRICAL CHARACTERISTICS (continued)

4.5V ≤ V(PVCC, AVCC) ≤ 17V, −40°C < T<sub>J</sub> + 125°C, typical values are at T<sub>A</sub> = 25°C, with respect to AGND (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>BAT OVER-VOLTAGE COMPARATOR</b>						
V <sub>OV_RISE</sub>	Over-voltage rising threshold	As percentage of V <sub>BAT_REG</sub> (bq24170) or V <sub>FB_REG</sub> (bq24172)		104%		
V <sub>OV_FALL</sub>	Over-voltage falling threshold	As percentage of V <sub>SRN</sub> (bq24170) or V <sub>FB_REG</sub> (bq24172)		102%		
<b>INPUT OVER-VOLTAGE COMPARATOR (ACOV)</b>						
V <sub>ACOV</sub>	AC Over-Voltage Rising Threshold to turn off ACFET	OVPSET rising	1.57	1.6	1.63	V
V <sub>ACOV_HYS</sub>	AC over-voltage falling hysteresis	OVPSET falling		50		mV
t <sub>ACOV_RISE_DEG</sub>	AC Over-Voltage Rising Deglitch to turn off ACFET and Disable Charge	OVPSET rising		1		μs
t <sub>ACOV_FALL_DEG</sub>	AC Over-Voltage Falling Deglitch to Turn on ACFET	OVPSET falling		30		ms
<b>INPUT UNDER-VOLTAGE COMPARATOR (ACUV)</b>						
V <sub>ACUV</sub>	AC Under-Voltage Falling Threshold to turn off ACFET	OVPSET falling	0.487	0.497	0.507	V
V <sub>ACUV_HYS</sub>	AC Under-Voltage Rising Hysteresis	OVPSET rising		100		mV
t <sub>ACOV_FALL_DEG</sub>	AC Under-Voltage Falling Deglitch to turn off ACFET and Disable Charge	OVPSET falling		1		μs
t <sub>ACOV_RISE_DEG</sub>	AC Under-Voltage Rising Deglitch to turn on ACFET	OVPSET rising		30		ms
<b>THERMAL REGULATION</b>						
T <sub>J_REG</sub>	Junction Temperature Regulation Accuracy	ISET > 120mV, Charging		120		°C
<b>THERMAL SHUTDOWN COMPARATOR</b>						
T <sub>SHUT</sub>	Thermal shutdown rising temperature	Temperature rising		150		°C
T <sub>SHUT_HYS</sub>	Thermal shutdown hysteresis	Temperature falling		20		°C
t <sub>SHUT_RISE_DEG</sub>	Thermal shutdown rising deglitch	Temperature rising		100		μs
t <sub>SHUT_FALL_DEG</sub>	Thermal shutdown falling deglitch	Temperature falling		10		ms
<b>THERMISTOR COMPARATOR</b>						
V <sub>LTF</sub>	Cold Temperature Threshold, TS pin Voltage Rising Threshold	Charger suspends charge. As percentage to V <sub>VREF</sub>	72.5%	73.5%	74.5%	
V <sub>LTF_HYS</sub>	Cold Temperature Hysteresis, TS pin Voltage Falling	As percentage to V <sub>VREF</sub>	0.2%	0.4%	0.6%	
V <sub>HTF</sub>	Hot Temperature TS pin voltage rising Threshold	As percentage to V <sub>VREF</sub>	46.6%	47.2%	48.8%	
V <sub>TCO</sub>	Cut-off Temperature TS pin voltage falling Threshold	As percentage to V <sub>VREF</sub>	44.2%	44.7%	45.2%	
t <sub>TS_CHG_SUS</sub>	Deglitch time for Temperature Out of Range Detection	V <sub>TS</sub> > V <sub>LTF</sub> , or V <sub>TS</sub> < V <sub>TCO</sub> , or V <sub>TS</sub> < V <sub>HTF</sub>		20		ms
t <sub>TS_CHG_RESUME</sub>	Deglitch time for Temperature in Valid Range Detection	V <sub>TS</sub> < V <sub>LTF</sub> – V <sub>LTF_HYS</sub> or V <sub>TS</sub> > V <sub>TCO</sub> , or V <sub>TS</sub> > V <sub>HTF</sub>		400		ms
<b>CHARGE OVER-CURRENT COMPARATOR (CYCLE-BY-CYCLE)</b>						
V <sub>OCP_CHRG</sub>	Charge Over-Current Rising Threshold, V <sub>SRP</sub> >2.2V	Current as percentage of fast charge current		160%		
V <sub>OCP_MIN</sub>	Charge Over-Current Limit Min, V <sub>SRP</sub> <2.2V	Measure V <sub>SRP-SRN</sub>		45		mV
V <sub>OCP_MAX</sub>	Charge Over-Current Limit Max, V <sub>SRP</sub> >2.2V	Measure V <sub>SRP-SRN</sub>		75		mV
<b>HSFET OVER-CURRENT COMPARATOR (CYCLE-BY-CYCLE)</b>						
I <sub>OCP_HSFET</sub>	Current limit on HSFET	Measure on HSFET	8	11.5		A
<b>CHARGE UNDER-CURRENT COMPARATOR (CYCLE-BY-CYCLE)</b>						
V <sub>UCP</sub>	Charge under-current falling threshold	Measure on V <sub>(SRP-SRN)</sub>	1	5	9	mV

## ELECTRICAL CHARACTERISTICS (continued)

4.5V ≤ V(PVCC, AVCC) ≤ 17V, −40°C < T<sub>J</sub> + 125°C, typical values are at T<sub>A</sub> = 25°C, with respect to AGND (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>BAT SHORT COMPARATOR</b>						
V <sub>BATSHOT</sub>	Battery short falling threshold	Measure on SRN		2		V
V <sub>BATSHOT_HYS</sub>	Battery short rising hysteresis	Measure on SRN		200		mV
t <sub>BATSHOT_DEG</sub>	Deglitch on both edges			1		μs
V <sub>BATSHOT</sub>	Charge Current during BATSHORT	Percentage of fast charge current		10% <sup>(4)</sup>		
<b>VREF REGULATOR</b>						
V <sub>VREF_REG</sub>	VREF regulator voltage	V <sub>AVCC</sub> > V <sub>UVLO</sub> , No load	3.267	3.3	3.333	V
I <sub>VREF_LIM</sub>	VREF current limit	V <sub>VREF</sub> = 0 V, V <sub>AVCC</sub> > V <sub>UVLO</sub>	35		90	mA
<b>REGN REGULATOR</b>						
V <sub>REGN_REG</sub>	REGN regulator voltage	V <sub>AVCC</sub> > 10 V, ISET > 120 mV	5.7	6.0	6.3	V
I <sub>REGN_LIM</sub>	REGN current limit	V <sub>REGN</sub> = 0 V, V <sub>AVCC</sub> > 10 v, ISET > 120 mV	40		120	mA
<b>TTC INPUT</b>						
t <sub>prechg</sub>	Precharge Safety Timer	Precharge time before fault occurs	1620	1800	1980	Sec
t <sub>fastchg</sub>	Fast Charge Timer Range	T <sub>chg</sub> = C <sub>TTC</sub> * K <sub>TTC</sub>	1		10	hr
	Fast Charge Timer Accuracy		-10%		10%	
K <sub>TTC</sub>	Timer Multiplier			5.6		min/nF
V <sub>TTC_LOW</sub>	TTC Low Threshold	TTC falling			0.4	V
I <sub>TTC</sub>	TTC Source/Sink Current		45	50	55	μA
V <sub>TTC_OSC_HI</sub>	TTC oscillator high threshold			1.5		V
V <sub>TTC_OSC_LO</sub>	TTC oscillator low threshold			1		V
<b>BATTERY SWITCH (BATFET) DRIVER</b>						
R <sub>DS_BAT_OFF</sub>	BATFET Turn-off Resistance	V <sub>AVCC</sub> > 5V			100	Ω
R <sub>DS_BAT_ON</sub>	BATFET Turn-on Resistance	V <sub>AVCC</sub> > 5V			20	kΩ
V <sub>BATDRV_REG</sub>	BATFET Drive Voltage	V <sub>BATDRV_REG</sub> = V <sub>ACN</sub> - V <sub>BATDRV</sub> when V <sub>AVCC</sub> > 5V and BATFET is on	4.2		7	V
t <sub>BATFET_DEG</sub>	BATFET Power-up Delay to turn off BATFET after adapter is detected			30		ms
<b>AC SWITCH (ACFET) DRIVER</b>						
I <sub>ACFET</sub>	ACDRV Charge Pump Current Limit	V <sub>ACDRV</sub> - V <sub>CMsrc</sub> = 5V		60		μA
V <sub>ACDRV_REG</sub>	Gate Drive Voltage on ACFET	V <sub>ACDRV</sub> - V <sub>CMsrc</sub> when V <sub>AVCC</sub> > V <sub>UVLO</sub>	4.2	6		V
R <sub>ACDRV_LOAD</sub>	Maximum load between ACDRV and CMsrc		500			kΩ
<b>AC/BAT SWITCH DRIVER TIMING</b>						
t <sub>DRV_DEAD</sub>	Driver Dead Time	Dead Time when switching between ACFET and BATFET		10		μs
<b>BATTERY DETECTION</b>						
t <sub>WAKE</sub>	Wake timer	Max time charge is enabled		500		ms
I <sub>WAKE</sub>	Wake current	R <sub>SENSE</sub> = 10 mΩ	50	125	200	mA
t <sub>DISCHARGE</sub>	Discharge timer	Max time discharge current is applied		1		sec
I <sub>DISCHARGE</sub>	Discharge current			8		mA
I <sub>FAULT</sub>	Fault current after a timeout fault			2		mA
V <sub>WAKE</sub>	Wake threshold with respect to V <sub>REG</sub> To detect battery absent during WAKE	Measure on SRN (bq24170)		100		mV/cell
		Measure on FB (bq24172)		50		mV
V <sub>DISCH</sub>	Discharge Threshold to detect battery absent during discharge	Measure on SRN (bq24170)		2.9		V/cell
		Measure on VFB (bq24172)		1.45		V

(4) The minimum current is 120 mA on 10mΩ sense resistor.

## ELECTRICAL CHARACTERISTICS (continued)

4.5V ≤ V(PVCC, AVCC) ≤ 17V, −40°C < T<sub>J</sub> + 125°C, typical values are at T<sub>A</sub> = 25°C, with respect to AGND (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>INTERNAL PWM</b>						
f <sub>SW</sub>	PWM Switching Frequency		1360	1600	1840	kHz
t <sub>SW_DEAD</sub>	Driver Dead Time <sup>(5)</sup>	Dead time when switching between LSFET and HSFET no load		30		ns
R <sub>DS_HI</sub>	High Side MOSFET On Resistance	V <sub>BTST</sub> – V <sub>SW</sub> = 4.5 V		25	45	mΩ
R <sub>DS_LO</sub>	Low Side MOSFET On Resistance			60	110	mΩ
V <sub>BTST_REFRESH</sub>	Bootstrap Refresh Comparator Threshold Voltage	V <sub>BTST</sub> – V <sub>SW</sub> when low side refresh pulse is requested, V <sub>AVCC</sub> =4.5V	3			V
		V <sub>BTST</sub> – V <sub>SW</sub> when low side refresh pulse is requested, V <sub>AVCC</sub> >6V	4			
<b>INTERNAL SOFT START (8 steps to regulation current ICHG)</b>						
SS_STEP	Soft start steps			8		step
T <sub>SS_STEP</sub>	Soft start step time			1.6	3	ms
<b>CHARGER SECTION POWER-UP SEQUENCING</b>						
t <sub>CE_DELAY</sub>	Delay from ISET above 120mV to start charging battery			1.5		s
<b>INTEGRATED BTST DIODE</b>						
V <sub>F</sub>	Forward Bias Voltage	I <sub>F</sub> =120mA at 25°C		0.85		V
V <sub>R</sub>	Reverse breakdown voltage	I <sub>R</sub> =2uA at 25°C			20	V
<b>LOGIC IO PIN CHARACTERISTICS (STAT1, STAT2, TERM_EN)</b>						
V <sub>OUT_LO</sub>	STAT Output Low Saturation Voltage	Sink Current = 5 mA			0.5	V
V <sub>CELL_LO</sub>	CELL pin input low threshold, 1 cell (bq24170)	CELL pin voltage falling edge			0.5	V
V <sub>CELL_MID</sub>	CELL pin input mid threshold, 2 cells (bq24170)	CELL pin voltage rising for MIN, falling for MAX	0.8		1.8	V
V <sub>CELL_HI</sub>	CELL pin input high threshold, 3 cells (bq24170)	CELL pin voltage rising edge	2.5			V

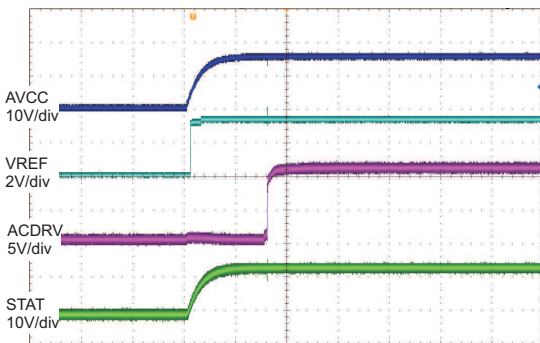
(5) Specified by design

## TYPICAL CHARACTERISTICS

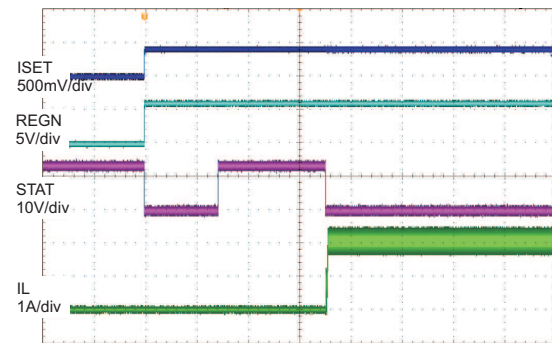
Table 1. Table of Graphs<sup>(1)</sup>

FIGURE	DESCRIPTION
<a href="#">Figure 5</a>	AVCC, VREF, ACDRV and STAT Power Up (ISET=0)
<a href="#">Figure 6</a>	Charge Enable by ISET
<a href="#">Figure 7</a>	Current Soft Start
<a href="#">Figure 8</a>	Charge Disable by ISET
<a href="#">Figure 9</a>	Continuous Conduction Mode Switching
<a href="#">Figure 10</a>	Discontinuous Conduction Mode Switching
<a href="#">Figure 11</a>	BATFET to ACFET Transition during Power Up
<a href="#">Figure 12</a>	System Load Transient (Input Current DPM)
<a href="#">Figure 13</a>	Battery Insertion and Removal
<a href="#">Figure 14</a>	Battery to Ground Short Protection
<a href="#">Figure 15</a>	Battery to Ground Short Transition
<a href="#">Figure 16</a>	Efficiency vs Output Current (VIN=15V)
<a href="#">Figure 17</a>	Efficiency vs Output Current (VOUT=3.8V)

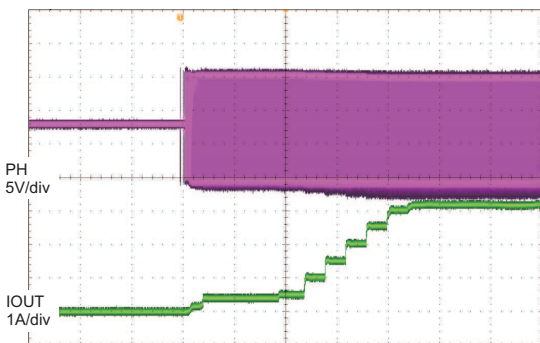
(1) All waveforms and data are measured on HPA610 and HPA706 EVMs.



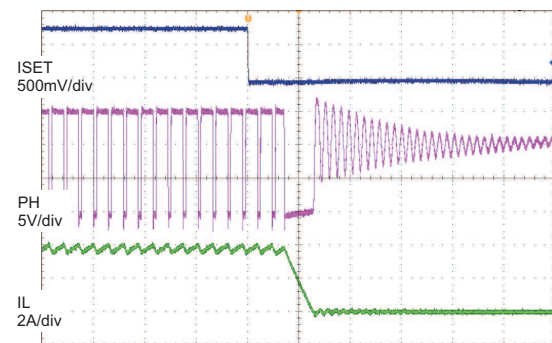
20 ms/div  
Figure 5. Power Up (ISET = 0)



400 ms/div  
Figure 6. Charge Enable by ISET

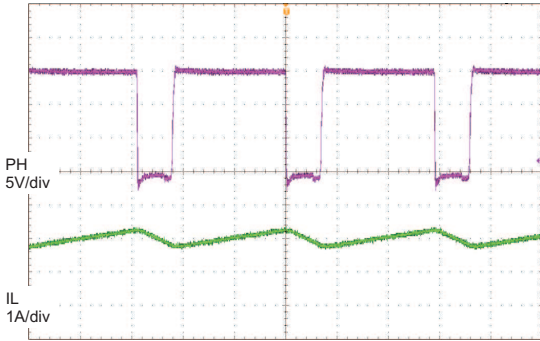


4 ms/div  
Figure 7. Current Soft Start



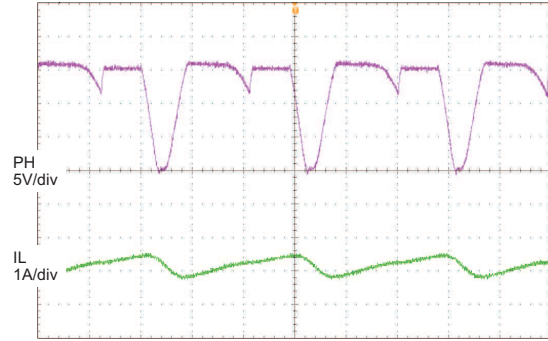
2 μs/div  
Figure 8. Charge Disable by ISET





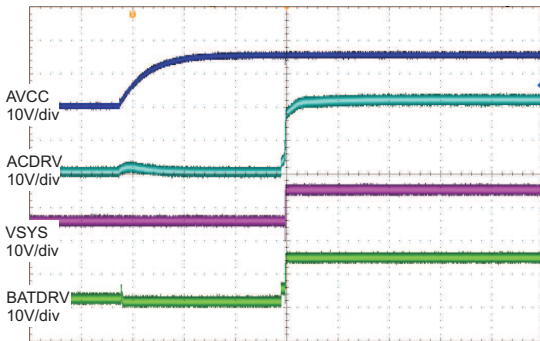
200 ns/div

Figure 9. Continuous Conduction Mode Switching



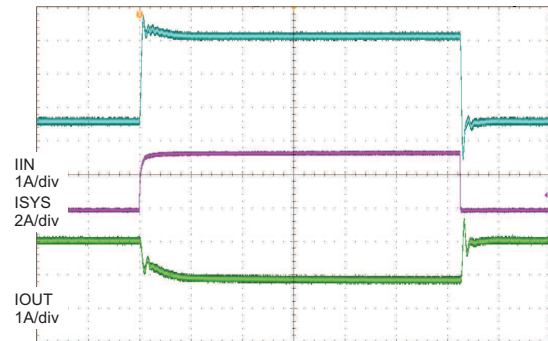
200 ns/div

Figure 10. Discontinuous Conduction Mode Switching



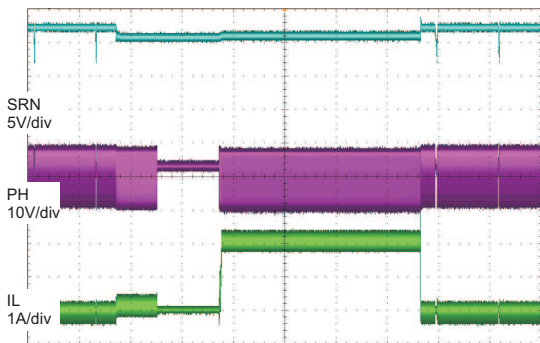
10 ms/div

Figure 11. BATFET to ACFET Transition During Powerup



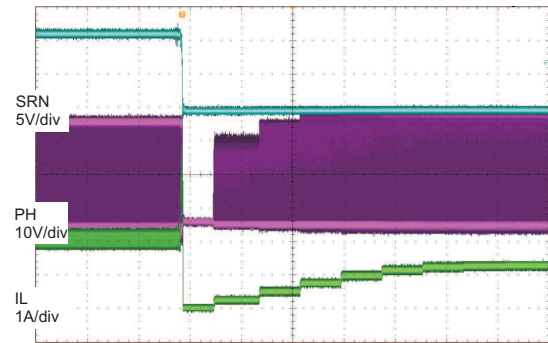
200  $\mu$ s/div

Figure 12. System Load Transient (Input current DPM)



400 ms/div

Figure 13. Battery Insertion and Removal



2 ms/div

Figure 14. Battery to Ground Short Protection

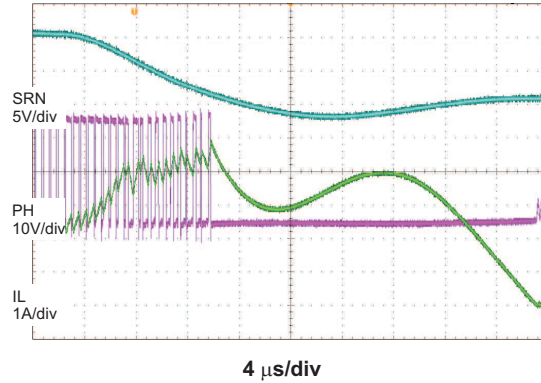


Figure 15. Battery to Ground Short Transition

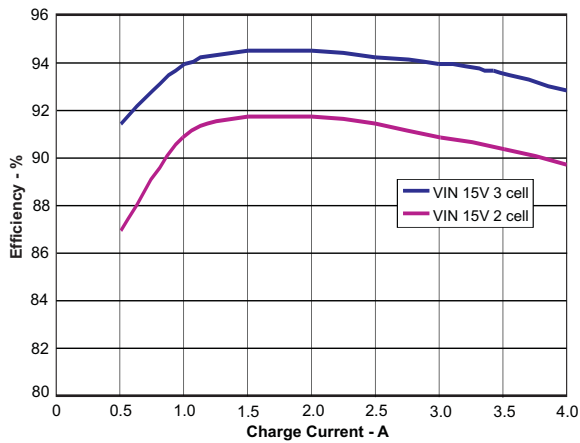


Figure 16. Efficiency vs Output Current (VIN = 15V)

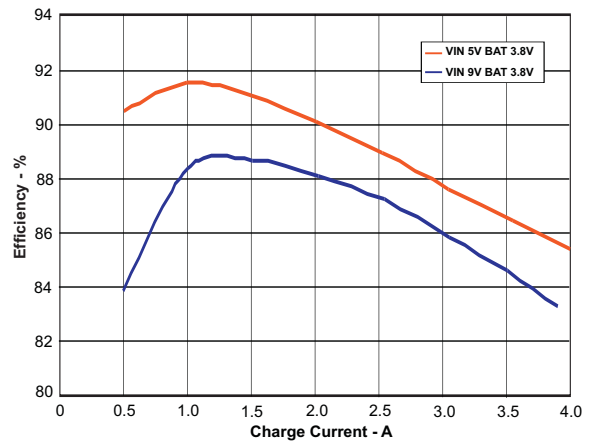


Figure 17. Efficiency vs Output Current (VOUT = 3.8V)



FUNCTIONAL BLOCK DIAGRAM

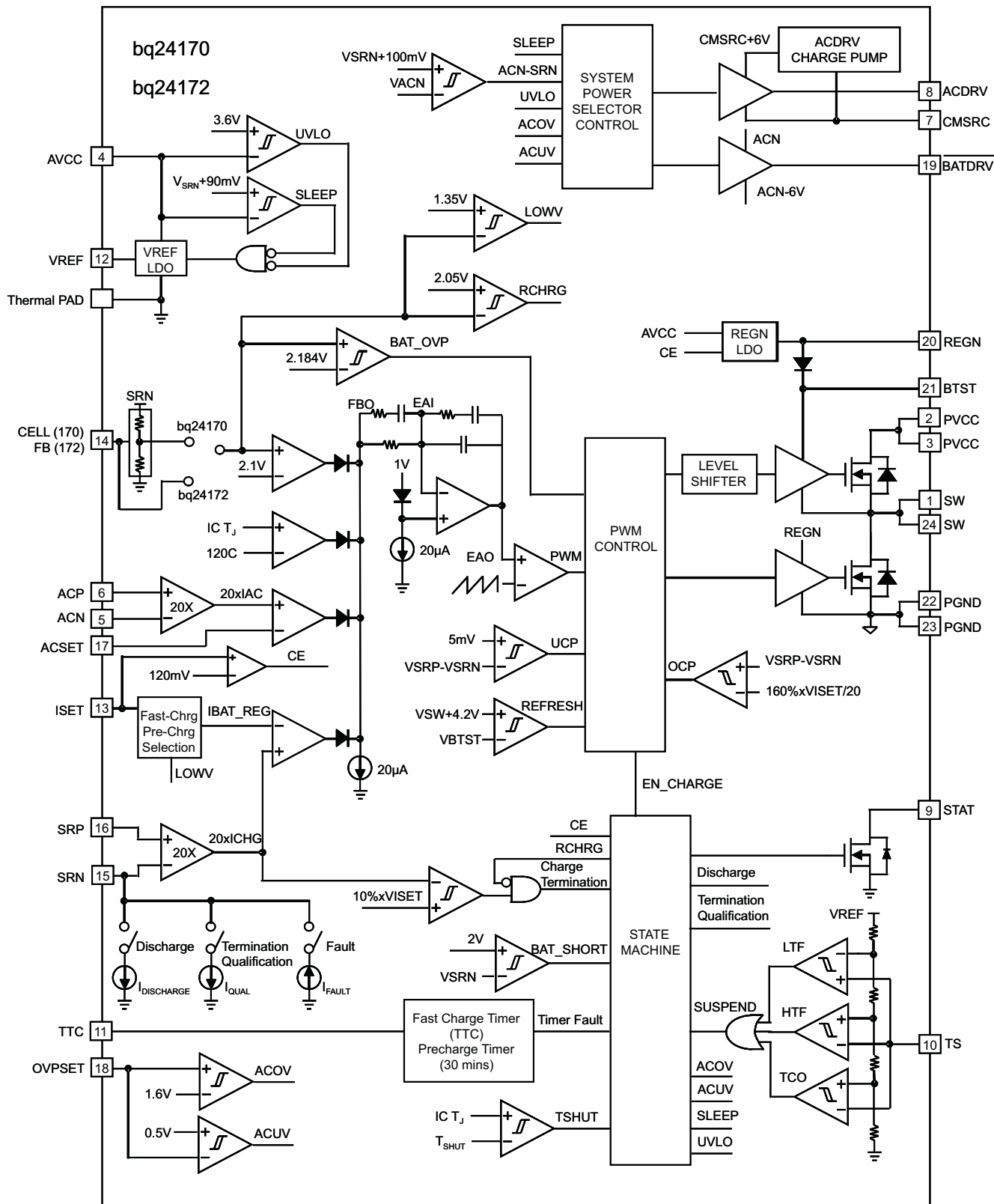


Figure 18. Functional Block Diagram

## DETAILED DESCRIPTION

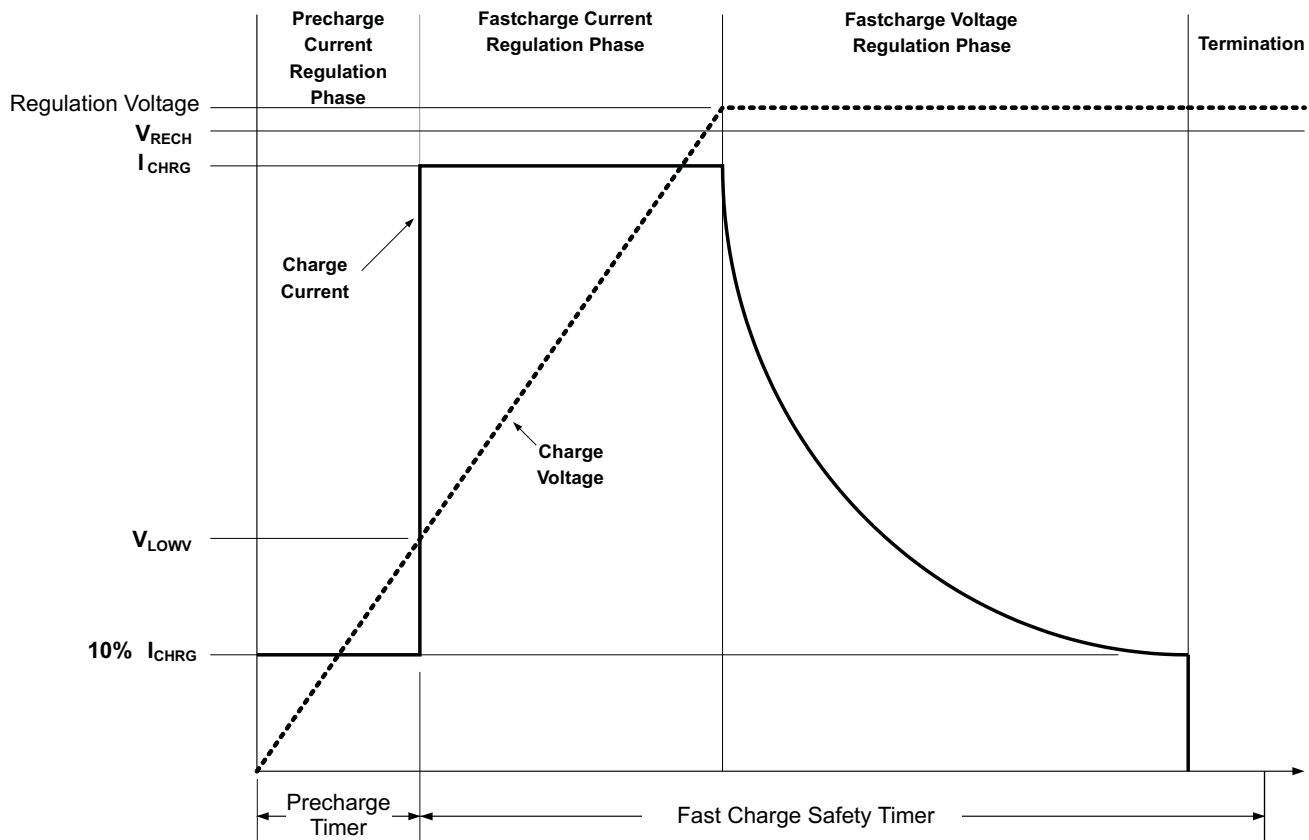


Figure 19. Typical Charging Profile

## BATTERY VOLTAGE REGULATION

The bq24170/172 offers a high accuracy voltage regulator on for the charging voltage. The bq24170 uses CELL pin to select number of cells with a fixed 4.2V/cell. Connecting CELL to AGND sets 1 cell output, floating CELL pin sets 2 cell output, and connecting to VREF sets 3 cell output.

Table 2. bq24170 CELL Pin Settings

CELL PIN	VOLTAGE REGULATION
AGND	4.2V
Floating	8.4 V
VREF	12.6 V

The bq24172 uses external resistor divider for voltage feedback and regulate to internal 2.1V voltage reference on FB pin. Use the following equation for the regulation voltage for bq24172:

$$V_{BAT} = 2.1 \text{ V} \times \left[ 1 + \frac{R2}{R1} \right] \quad (1)$$

where R2 is connected from FB to the battery and R1 is connected from FB to GND.

## BATTERY CURRENT REGULATION

The ISET input sets the maximum charging current. Battery current is sensed by current sensing resistor RSR connected between SRP and SRN. The full-scale differential voltage between SRP and SRN is 40mV max. The equation for charge current is:

$$I_{\text{CHARGE}} = \frac{V_{\text{ISET}}}{20 \times R_{\text{SR}}} \quad (2)$$

The valid input voltage range of ISET is up to 0.8V. With 10mΩ sense resistor, the maximum output current is 4A. With 20mΩ sense resistor, the maximum output current is 2A.

The charger is disabled when ISET pin voltage is below 40mV and is enabled when ISET pin voltage is above 120mV. For 10mΩ current sensing resistor, the minimum fast charge current must be higher than 600mA.

Under high ambient temperature, the charge current will fold back to keep IC temperature not exceeding 120°C.

## BATTERY PRECHARGE CURRENT REGULATION

On Power-up, if the battery voltage is below the  $V_{\text{LOWV}}$  threshold, the bq24170/172 applies the pre-charge current to the battery. This pre-charge feature is intended to revive deeply discharged cells. If the  $V_{\text{LOWV}}$  threshold is not reached within 30 minutes of initiating pre-charge, the charger turns off and a FAULT is indicated on the status pins.

For bq24170/172, the pre-charge current is set as 10% of the fast charge rate set by ISET voltage.

$$I_{\text{PRECHARGE}} = \frac{V_{\text{ISET}}}{200 \times R_{\text{SR}}} \quad (3)$$

## INPUT CURRENT REGULATION

The total input current from an AC adapter or other DC sources is a function of the system supply current and the battery charging current. System current normally fluctuates as portions of the systems are powered up or down. Without Dynamic Power Management (DPM), the source must be able to supply the maximum system current and the maximum available charger input current simultaneously. By using DPM, the input current regulator reduces the charging current when the summation of system power and charge power exceeds the maximum input power. Therefore, the current capability of the AC adapter can be lowered, reducing system cost.

Input current is set by the voltage on ACSET pin using the following equation:

$$I_{\text{DPM}} = \frac{V_{\text{ACSET}}}{20 \times R_{\text{AC}}} \quad (4)$$

The ACP and ACN pins are used to sense across RAC with default value of 10mΩ. However, resistors of other values can also be used. A larger sense resistor will give a larger sense voltage and higher regulation accuracy, at the expense of higher conduction loss.

## CHARGE TERMINATION, RECHARGE, AND SAFETY TIMERS

The charger monitors the charging current during the voltage regulation phase. Termination is detected when the SRN voltage (bq24170) or FB voltage (bq24172) is higher than recharge threshold and the charge current is less than the termination current threshold, as calculated below:

$$I_{\text{TERM}} = \frac{V_{\text{ISET}}}{200 \times R_{\text{SR}}} \quad (5)$$

where  $V_{\text{ISET}}$  is the voltage on the ISET pin and  $R_{\text{SR}}$  is the sense resistor. There is a 25ms deglitch time during transition between fast-charge and pre-charge.

As a safety backup, the charger also provides an internal fixed 30 minutes pre-charge safety timer and a programmable fast charge timer. The fast charge time is programmed by the capacitor connected between the TTC pin and AGND, and is given by the formula:

$$t_{\text{TTC}} = C_{\text{TTC}} \times K_{\text{TTC}} \quad (6)$$

Where  $C_{\text{TTC}}$  is the capacitor connected to TTC and  $K_{\text{TTC}}$  is the constant multiplier.

A new charge cycle is initiated when one of the following conditions occurs:

- The battery voltage falls below the recharge threshold
- A power-on-reset (POR) event occurs
- ISET pin toggled below 40mV (disable charge) and above 120mV (enable charge)

Pull TTC pin to AGND to disable both termination and fast charge safety timer (reset timer). Pull TTC pin to VREF to disable the safety timer, but allow charge termination.

## POWER UP

The charge uses a SLEEP comparator to determine the source of power on the AVCC pin, since AVCC can be supplied either from the battery or the adapter. With the adapter source present, if the AVCC voltage is greater than the SRN voltage, the charger exits SLEEP mode. If all conditions are met for charging, the charger then starts charge the battery (see *the Enabling and Disabling Charging* section). If SRN voltage is greater than AVCC, the charger enters low quiescent current SLEEP mode to minimize current drain from the battery. During SLEEP mode, the VREF output turns off and the STAT pin goes to high impedance.

If AVCC is below the UVLO threshold, the device is disabled.

## INPUT UNDER-VOLTAGE LOCK-OUT (UVLO)

The system must have a minimum AVCC voltage to allow proper operation. This AVCC voltage could come from either input adapter or battery, since a conduction path exists from the battery to AVCC through the high side NMOS body diode. When AVCC is below the UVLO threshold, all circuits on the IC are disabled.

## INPUT OVER-VOLTAGE/UNDER-VOLTAGE PROTECTION

ACOV provides protection to prevent system damage due to high input voltage. In bq24170/172, once the voltage on OVPSET is above the 1.6V ACOV threshold or below the 0.5V ACUV threshold, charge is disabled and input MOSFETs turn off. The bq24170/172 provides flexibility to set the input qualification threshold.

## ENABLE AND DISABLE CHARGING

The following conditions have to be valid before charging is enabled:

- ISET pin above 120mV
- Device is not in Under-Voltage-Lock-Out (UVLO) mode (i.e.  $V_{AVCC} > V_{UVLO}$ )
- Device is not in SLEEP mode (i.e.  $V_{AVCC} > V_{SRN}$ )
- OVPSET voltage is between 0.5V and 1.6V to qualify the adapter
- 1.5s delay is complete after initial power-up
- REGN LDO and VREF LDO voltages are at correct levels
- Thermal Shut down (TSHUT) is not valid
- TS fault is not detected
- ACFET turns on (See *System Power Selector* for details)

One of the following conditions stops on-going charging:

- ISET pin voltage is below 40mV
- Device is in UVLO mode
- Adapter is removed, causing the device to enter SLEEP mode
- OVPSET voltage indicates the adapter is not valid
- REGN or VREF LDO voltage is overloaded
- TSHUT temperature threshold is reached
- TS voltage goes out of range indicating the battery temperature is too hot or too cold
- ACFET turns off
- TTC timer expires or pre-charge timer expires

## SYSTEM POWER SELECTOR

The IC automatically switches adapter or battery power to the system load. The battery is connected to the system by default during power up or during SLEEP mode. When the adapter plugs in and the voltage is above the battery voltage, the IC exits SLEEP mode. The battery is disconnected from the system and the adapter is connected to the system after exiting SLEEP. An automatic break-before-make logic prevents shoot-through currents when the selectors switch.

The ACDRV is used to drive a pair of back-to-back n-channel power MOSFETs between adapter and ACP with sources connected together to CMSRC. The n-channel FET with the drain connected to the ACP (Q2, RBFET) provides reverse battery discharge protection, and minimizes system power dissipation with its low-RDS<sub>ON</sub>. The other n-channel FET with drain connected to adapter input (Q1, ACFET) separates battery from adapter, and provides a limited di/dt when connecting the adapter to the system by controlling the FET turn-on time. The /BATDRV controls a p-channel power MOSFET (Q3, BATFET) placed between battery and system with drain connected to battery.

Before the adapter is detected, the ACDRV is pulled to CMSRC to keep ACFET off, disconnecting the adapter from system. /BATDRV stays at ACN-6V (clamp to ground) to connect battery to system if all the following conditions are valid:

- $V_{AVCC} > V_{UVLO}$  (battery supplies AVCC)
- $V_{ACN} < V_{SRN} + 200 \text{ mV}$

After the device comes out of SLEEP mode, the system begins to switch from battery to adapter. The AVCC voltage has to be 300mV above SRN to enable the transition. The break-before-make logic keeps both ACFET and BATFET off for 10us before ACFET turns on. This prevents shoot-through current or any large discharging current from going into the battery. The /BATDRV is pulled up to ACN and the ACDRV pin is set to CMSRC + 6V by an internal charge pump to turn on n-channel ACFET, connecting the adapter to the system if all the following conditions are valid:

- $V_{ACUV} < V_{OVPSSET} < V_{ACOV}$
- $V_{AVCC} > V_{SRN} + 300 \text{ mV}$

When the adapter is removed, the IC turns off ACFET and enters SLEEP mode.

BATFET keeps off until the system drops close to SRN. The  $\overline{\text{BATDRV}}$  pin is driven to ACN - 6V by an internal regulator to turn on p-channel BATFET, connecting the battery to the system.

Asymmetrical gate drive provides fast turn-off and slow turn-on of the ACFET and BATFET to help the break-before-make logic and to allow a soft-start at turn-on of both MOSFETs. The delay time can be further increased, by putting a capacitor from gate to source of the power MOSFETs.

## CONVERTER OPERATION

The bq24170/172 employs a 1.6MHz constant-frequency step-down switching regulator. The fixed frequency oscillator keeps tight control of the switching frequency under all conditions of input voltage, battery voltage, charge current, and temperature, simplifying output filter design and keeping it out of the audible noise region.

A type III compensation network allows using ceramic capacitors at the output of the converter. An internal saw-tooth ramp is compared to the internal error control signal to vary the duty-cycle of the converter. The ramp height is proportional to the AVCC voltage to cancel out any loop gain variation due to a change in input voltage, and simplifies the loop compensation. Internal gate drive logic allows achieving 97% duty-cycle before pulse skipping starts.

## AUTOMATIC INTERNAL SOFT-START CHARGER CURRENT

The charger automatically soft-starts the charger regulation current every time the charger goes into fast-charge to ensure there is no overshoot or stress on the output capacitors or the power converter. The soft-start consists of stepping-up the charge regulation current into 8 evenly divided steps up to the programmed charge current. Each step lasts around 1.6ms, for a typical rise time of 12.8ms. No external components are needed for this function.

## CHARGE OVER-CURRENT PROTECTION

The charger monitors top side MOSFET current by high side sense FET. When peak current exceeds MOSFET limit, it will turn off the top side MOSFET and keep it off until the next cycle. The charger has a secondary cycle-to-cycle over-current protection. It monitors the charge current, and prevents the current from exceeding 160% of the programmed charge current. The high-side gate drive turns off when either over-current condition is detected, and automatically resumes when the current falls below the over-current threshold.

## CHARGE UNDER-CURRENT PROTECTION

After the recharge, if the SRP-SRN voltage decreases below 5mV, the low side FET will be turned off for the rest of the switching cycle. During discontinuous conduction mode (DCM), the low side FET will only turn on for a short period of time when the bootstrap capacitor voltage drops below 4V to provide refresh charge for the capacitor. This is important to prevent negative inductor current from causing any boost effect in which the input voltage increases as power is transferred from the battery to the input capacitors. This can lead to an over-voltage on the AVCC node and potentially cause damage to the system.

## BATTERY DETECTION

For applications with removable battery packs, IC provides a battery absent detection scheme to reliably detect insertion or removal of battery packs. The battery detection routine runs on power up, or if battery voltage falls below recharge threshold voltage due to removing a battery or discharging a battery.

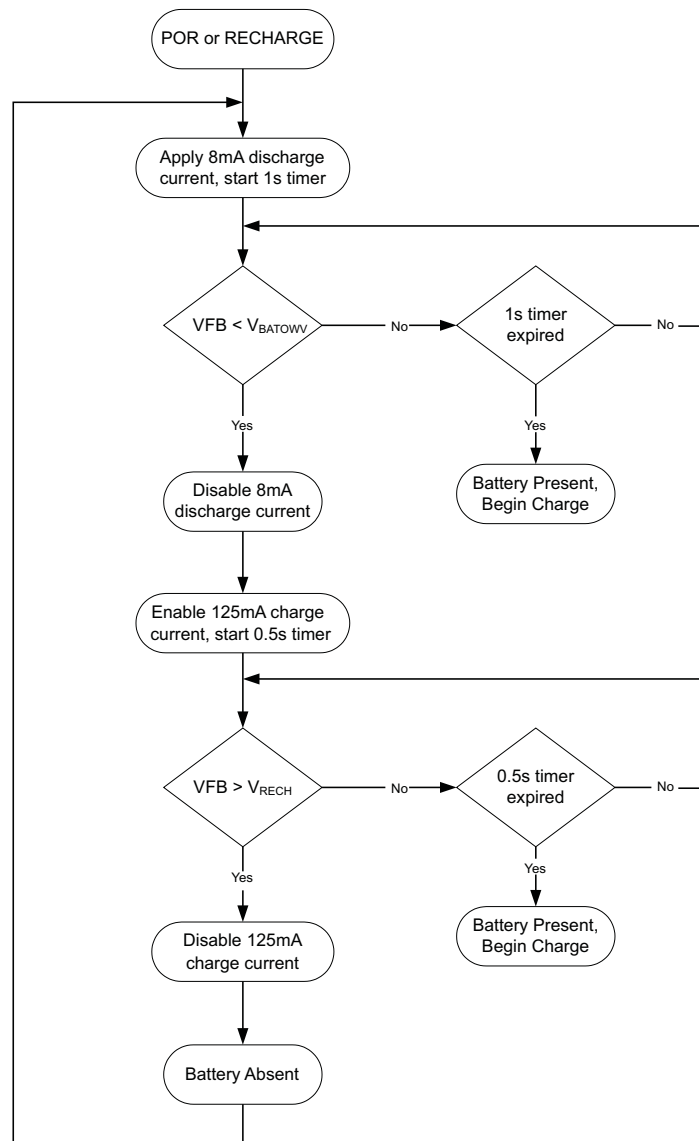
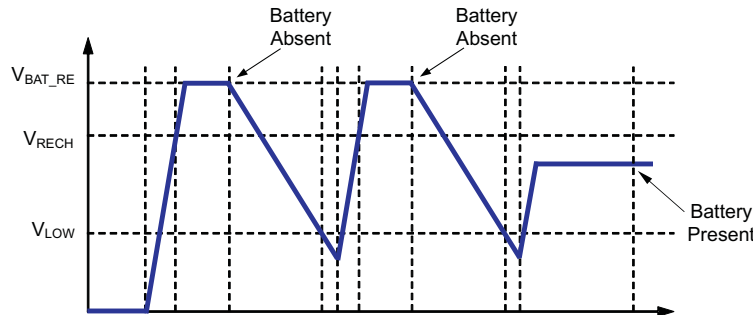


Figure 20. Battery Detection Flowchart

Once the device has powered up, a 8-mA discharge current is applied to the SRN terminal. If the battery voltage falls below the LOWV threshold within 1 second, the discharge source is turned off, and the charger is turned on at low charge current (125mA). If the battery voltage gets up above the recharge threshold within 500ms, there is no battery present and the cycle restarts. If either the 500ms or 1 second timer time out before the respective thresholds are hit, a battery is detected and a charge cycle is initiated.



**Figure 21. Battery Detect Timing Diagram**

Care must be taken that the total output capacitance at the battery node is not so large that the discharge current source cannot pull the voltage below the LOWV threshold during the 1 second discharge time. The maximum output capacitances can be calculated according to the following equations:

$$C_{MAX} = \frac{I_{DISCH} \times t_{DISCH}}{(4.1 \text{ V} - 2.9 \text{ V}) \times \text{Number of cells}} \quad (\text{for bq24170}) \quad (7)$$

$$C_{MAX} = \frac{I_{DISCH} \times t_{DISCH}}{(2.05 \text{ V} - 1.45 \text{ V}) \times \left[ 1 + \frac{R_2}{R_1} \right]} \quad (\text{for bq24172}) \quad (8)$$

Where  $C_{MAX}$  is the maximum output capacitance,  $I_{DISCH}$  is the discharge current,  $t_{DISCH}$  is the discharge time, and  $R_2$  and  $R_1$  are the voltage feedback resistors from the battery to the FB pin.

**Example**

For a 3-cell Li+ charger, with  $R_2 = 500\text{k}\Omega$ ,  $R_1 = 100\text{k}\Omega$  (giving 12.6V for voltage regulation),  $I_{DISCH} = 8\text{mA}$ ,  $t_{DISCH} = 1$  second.

$$C_{MAX} = \frac{8 \text{ mA} \times 1 \text{ sec}}{0.6 \text{ V} \times \left[ 1 + \frac{500 \text{ k}\Omega}{100 \text{ k}\Omega} \right]} = 2.2 \text{ mF} \quad (9)$$

Based on these calculations, no more than 2200  $\mu\text{F}$  should be allowed on the battery node for proper operation of the battery detection circuit.

**BATTERY SHORT PROTECTION**

When SRN pin voltage is lower than 2V it is considered as battery short condition during charging period. The charger will shut down immediately for 1ms, then soft start back to the charging current the same as precharge current. This prevents high current may build in output inductor and cause inductor saturation when battery terminal is shorted during charging. The converter works in non-synchronous mode during battery short.

**BATTERY OVER-VOLTAGE PROTECTION**

The converter will not allow the high-side FET to turn-on until the battery voltage goes below 102% of the regulation voltage. This allows one-cycle response to an over-voltage condition – such as occurs when the load is removed or the battery is disconnected. A total 6mA current sink from SRP/SRN to AGND allows discharging the stored output inductor energy that is transferred to the output capacitors. If battery over-voltage condition lasts for more than 30ms, charge is disabled.







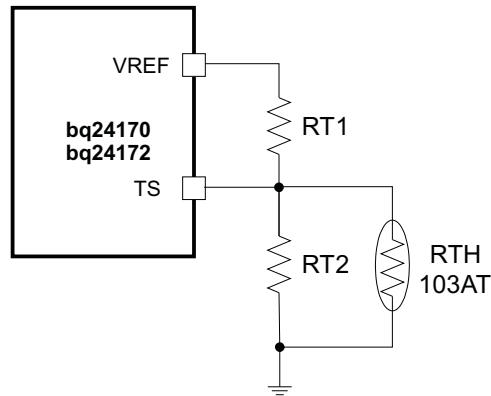


Figure 23. TS Resistor Network

## MOSFET SHORT CIRCUIT AND INDUCTOR SHORT CIRCUIT PROTECTION

The IC has a short circuit protection feature. Its cycle-by-cycle current monitoring feature is achieved through monitoring the voltage drop across  $R_{ds(on)}$  of the MOSFETs. The charger will be latched off, but the ACFET keep on to power the system. The only way to reset the charger from latch-off status is remove adapter then plug adapter in again. Meanwhile, STAT is blinking to report the fault condition.

## THERMAL REGULATION AND SHUTDOWN PROTECTION

The QFN package has low thermal impedance, which provides good thermal conduction from the silicon to the ambient, to keep junctions temperatures low. The internal thermal regulation loop will fold back the charge current to keep the junction temperature from exceeding 120°C. As added level of protection, the charger converter turns off and self-protects whenever the junction temperature exceeds the TSHUT threshold of 150°C. The charger stays off until the junction temperature falls below 130°C.

## TIMER FAULT RECOVERY

The IC provides a recovery method to deal with timer fault conditions. The following summarizes this method:

Condition 1: The battery voltage is above the recharge threshold and a timeout fault occurs.

Recovery Method: The timer fault will clear when the battery voltage falls below the recharge threshold, and battery detection will begin. A POR or taking ISET below 40mV will also clear the fault.

Condition 2: The battery voltage is below the recharge threshold and a timeout fault occurs.

Recovery Method: Under this scenario, the IC applies the fault current to the battery. This small current is used to detect a battery removal condition and remains on as long as the battery voltage stays below the recharge threshold. If the battery voltage goes above the recharge threshold, the IC disabled the fault current and executes the recovery method described in Condition 1. A POR or taking ISET below 40mV will also clear the fault.

## INDUCTOR, CAPACITOR, AND SENSE RESISTOR SELECTION GUIDELINES

The IC provides internal loop compensation. With this scheme, the best stability occurs when the LC resonant frequency,  $f_o$ , is approximately 15kHz – 25kHz for the IC.

$$f_o = \frac{1}{2\pi\sqrt{LC}} \quad (12)$$

Table 3 provides a summary of typical LC components for various charge currents.

**Table 3. Typical Values as a Function of Charge Current**

CHARGE CURRENT	1A	2A	3A	4A
Output inductor L	6.8 $\mu$ H	3.3 $\mu$ H	3.3 $\mu$ H	2.2 $\mu$ H
Output capacitor C	10 $\mu$ F	20 $\mu$ F	20 $\mu$ F	30 $\mu$ F

## CHARGE STATUS OUTPUTS

The open-drain STAT outputs indicate various charger operations as listed in Table 4. These status pins can be used to drive LEDs or communicate with the host processor. Note that OFF indicates that the open-drain transistor is turned off.

**Table 4. STAT Pin Definition**

CHARGE STATE	STAT
Charge in progress (including recharging)	ON
Charge complete, Sleep mode, Charge disabled	OFF
Charge suspend, Input over-voltage, Battery over-voltage, timer fault, , battery absent	BLINK

## APPLICATION INFORMATION

### INDUCTOR SELECTION

The bq24170/72 has a 1600-kHz switching frequency to allow the use of small inductor and capacitor values. Inductor saturation current should be higher than the charging current ( $I_{CHG}$ ) plus half the ripple current ( $I_{RIPPLE}$ ):

$$I_{SAT} \geq I_{CHG} + (1/2)I_{RIPPLE} \quad (13)$$

Inductor ripple current depends on input voltage ( $V_{IN}$ ), duty cycle ( $D = V_{OUT}/V_{IN}$ ), switching frequency ( $f_s$ ), and inductance ( $L$ ):

$$I_{RIPPLE} = \frac{V_{IN} \times D \times (1-D)}{f_s \times L} \quad (14)$$

The maximum inductor ripple current happens with  $D = 0.5$  or close to 0.5. Usually inductor ripple is designed in the range of 20% to 40% of the maximum charging current as a trade-off between inductor size and efficiency for a practical design.

### INPUT CAPACITOR

The input capacitor should have enough ripple current rating to absorb input switching ripple current. The worst case RMS ripple current is half of the charging current when duty cycle is 0.5. If the converter does not operate at 50% duty cycle, then the worst case capacitor RMS current  $I_{CIN}$  occurs where the duty cycle is closest to 50% and can be estimated by the following equation:

$$I_{CIN} = I_{CHG} \times \sqrt{D \times (1-D)} \quad (15)$$

A low ESR ceramic capacitor such as X7R or X5R is preferred for the input decoupling capacitor and should be placed as close as possible to the drain of the high-side MOSFET and source of the low-side MOSFET. The voltage rating of the capacitor must be higher than the normal input voltage level. A 25V rating or higher capacitor is preferred for a 15V input voltage. A 20 $\mu$ F capacitance is suggested for a typical 3A to 4A charging current.

### OUTPUT CAPACITOR

The output capacitor also should have enough ripple current rating to absorb output switching ripple current. The output capacitor RMS current  $I_{COUT}$  is given as:

$$I_{COUT} = \frac{I_{RIPPLE}}{2 \times \sqrt{3}} \approx 0.29 \times I_{RIPPLE} \quad (16)$$

The output capacitor voltage ripple can be calculated as follows:

$$\Delta V_O = \frac{V_{OUT}}{8LCf_s^2} \left( 1 - \frac{V_{OUT}}{V_{IN}} \right) \quad (17)$$

At certain input/output voltages and switching frequencies, the voltage ripple can be reduced by increasing the output filter LC.

The bq24170/72 has an internal loop compensator. To achieve good loop stability, the resonant frequency of the output inductor and output capacitor should be designed between 15 kHz and 25 kHz. The preferred ceramic capacitor has a 25V or higher rating, X7R or X5R.

### INPUT FILTER DESIGN

During adapter hot plug-in, the parasitic inductance and the input capacitor from the adapter cable form a second order system. The voltage spike at the AVCC pin may be beyond the IC maximum voltage rating and damage the IC. The input filter must be carefully designed and tested to prevent an over-voltage event on the AVCC pin.

There are several methods to damping or limiting the over-voltage spike during adapter hot plug-in. An electrolytic capacitor with high ESR as an input capacitor can damp the over-voltage spike well below the IC maximum pin voltage rating. A high current capability TVS Zener diode can also limit the over-voltage level to an IC safe level. However, these two solutions may not be lowest cost or smallest size.

A cost effective and small size solution is shown in Figure 24. R1 and C1 are composed of a damping RC network to damp the hot plug-in oscillation. As a result, the over-voltage spike is limited to a safe level. D1 is used for reverse voltage protection for the AVCC pin. C2 is the AVCC pin decoupling capacitor and it should be placed as close as possible to the AVCC pin. R2 and C2 form a damping RC network to further protect the IC from high dv/dt and high voltage spike. The C2 value should be less than the C1 value so R1 can dominant the equivalent ESR value to get enough damping effect for hot plug-in. R1 and R2 must be sized enough to handle in-rush current power loss according to the resistor manufacturer's datasheet. The filter component values always need to be verified with a real application and minor adjustments may be needed to fit in the real application circuit.

If the input is 5V (USB host or USB adapter), the D1 can be saved. R2 has to be 5Ω or higher to limit the current if the input reversely inserted.

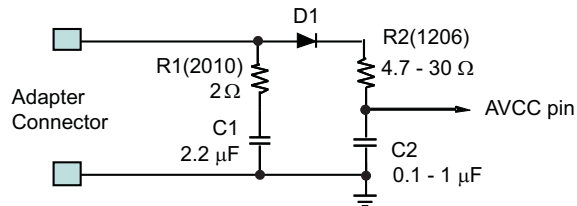


Figure 24. Input Filter

## INPUT ACFET AND RBFET SELECTION

N-type MOSFETs are used as input ACFET(Q1) and RBFET(Q2) for better cost effective and small size solution, as shown in Figure 22. Normally, there are around 50uF capacitor totally connected at PVCC node --- 10uF capacitor for buck converter of bq24170/2 and 40uF capacitor for system side. There is a surge current during Q1 turn-on period when a valid adapter is inserted. Decreasing the turn-on speed of Q1 can limit this surge current in desirable range by selecting a MOSFET with relative bigger  $C_{GD}$  and/or  $C_{GS}$ . At the case Q1 turn on too fast, we need add external  $C_{GD}$  and/or  $C_{GS}$ . For example, 4.7nF  $C_{GD}$  and 47nF  $C_{GS}$  are adopted on EVM while using NexFET CSD17313 as Q1.

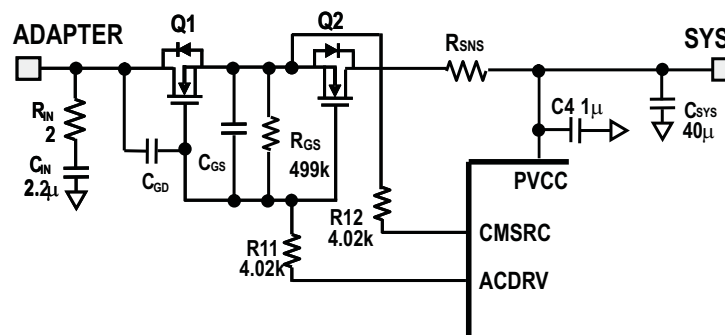


Figure 25. Input ACFET and RBFET

## PCB LAYOUT

The switching node rise and fall times should be minimized for minimum switching loss. Proper layout of the components to minimize the high frequency current path loop (see Figure 26) is important to prevent electrical and magnetic field radiation and high frequency resonant problems. The following is a PCB layout priority list for proper layout. Layout of the PCB according to this specific order is essential.

1. Place input capacitor as close as possible to the PVCC supply and ground connections and use the shortest copper trace connection. These parts should be placed on the same layer of the PCB instead of on different layers and using vias to make this connection.
2. Place the inductor input terminal as close as possible to the SW terminal. Minimize the copper area of this trace to lower electrical and magnetic field radiation but make the trace wide enough to carry the charging current. Do not use multiple layers in parallel for this connection. Minimize parasitic capacitance from this

- area to any other trace or plane.
- The charging current sensing resistor should be placed right next to the inductor output. Route the sense leads connected across the sensing resistor back to the IC in the same layer, close to each other (minimize loop area) and do not route the sense leads through a high-current path (see [Figure 27](#) for Kelvin connection for best current accuracy). Place decoupling capacitor on these traces next to the IC.
  - Place output capacitor next to the sensing resistor output and ground.
  - Output capacitor ground connections need to be tied to the same copper that connects to the input capacitor ground before connecting to system ground.
  - Route analog ground separately from power ground and use a single ground connection to tie charger analog ground to charger analog ground. Just beneath the IC use analog ground copper pour but avoid power pins to reduce inductive and capacitive noise coupling. Use the thermal pad as a single ground connection point to connect analog ground and power ground together, or use a 0-Ω resistor to tie analog ground to power ground. A star-connection under the thermal pad is highly recommended.
  - It is critical that the exposed thermal pad on the backside of the IC package be soldered to the PCB ground. Ensure that there are sufficient thermal vias directly under the IC, connecting to the ground plane on the other layers.
  - Decoupling capacitors should be placed next to the IC pins and make trace connection as short as possible.
  - The number and physical size of the vias should be enough for a given current path.

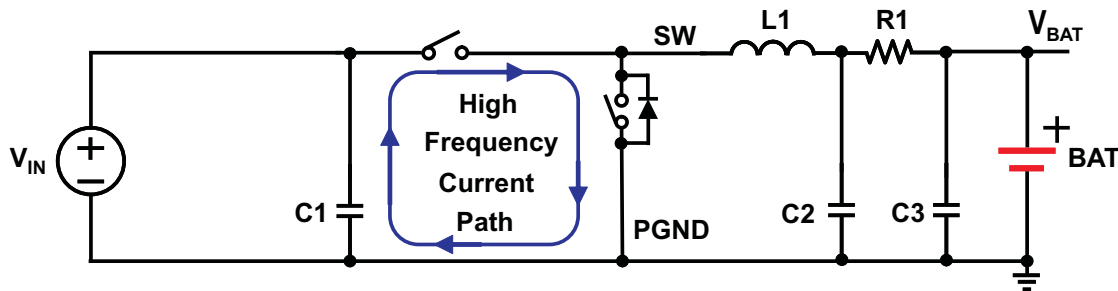


Figure 26. High Frequency Current Path

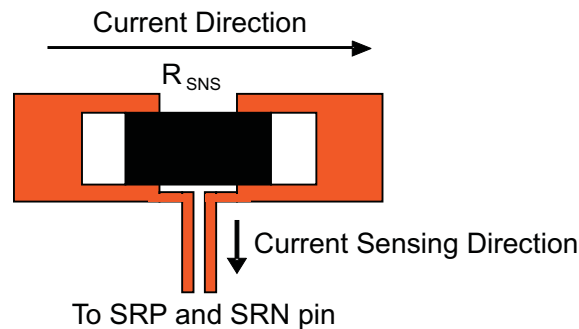


Figure 27. Sensing Resistor PCB Layout

## REVISION HISTORY

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**Changes from Original (November 2010) to Revision A** **Page**

- Changed status from product preview to production data ..... **1**
- 

**Changes from Revision A (November 2010) to Revision B** **Page**

- Changed FEATURES third bullet to 30V Input Rating with Adjustable Over-Voltage Protection and added sub-bullet: 4.5V to 17V Input Operating Voltage Range ..... **1**
  - Added a new paragraph in DESCRIPTION on page 2, second paragraph ..... **2**
  - Deleted last sentence in Pin NO. 19, Description column ..... **3**
  - Added diode between BTST and REGN pins in [Figure 3](#) ..... **6**
  - Added diode between BTST and REGN pins in [Figure 4](#) ..... **7**
  - Added 2nd row in the ABS MAX TABLE, moving AVCC,....STAT from first row to second row and adding -0.3 to 30 in Value column. Also moved ACDRV to this row from next row ..... **8**
  - Changed RECOMMENDED OPERATING CONDITIONS Output current row, MIN column from 600 to 0.6 ..... **8**
  - Changed MIN and MAX columns from 1.55 to 1.57, and 1.65 to 1.63 in first row under INPUT OVER-VOLTAGE COMPARATOR (ACOV) section in ELECTRICAL CHARACTERISTICS table ..... **11**
  - Changed MIN, TYP, MAX column from 0.45 to 0.487, 0.5 to 0.497 and 0.55 to 0.507 in first row under INPUT UNDER-VOLTAGE COMPARATOR (ACUV) section in ELECTRICAL CHARACTERISTICS table ..... **11**
  - Added paragraph to INPUT FILTER DESIGN section ..... **28**
-

RGY (R-PVQFN-N24)

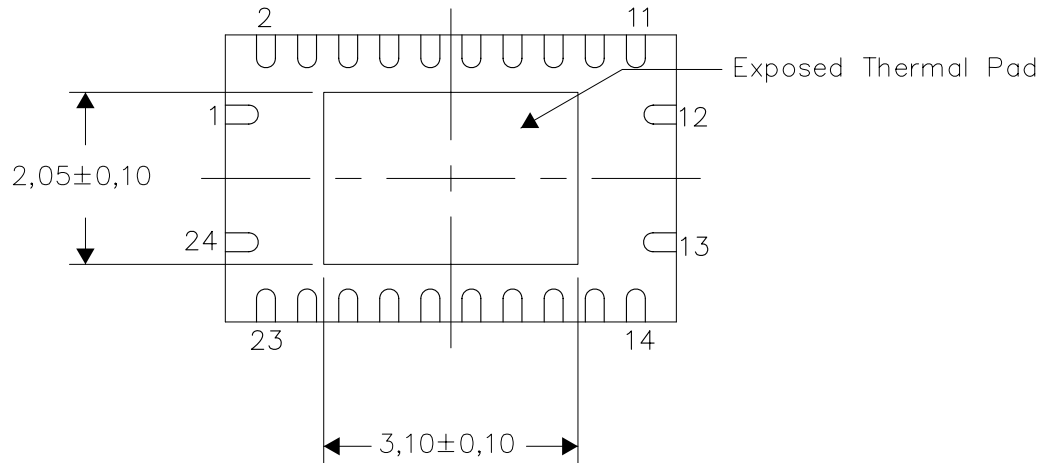
PLASTIC QUAD FLATPACK NO-LEAD

**THERMAL INFORMATION**

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at [www.ti.com](http://www.ti.com).

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

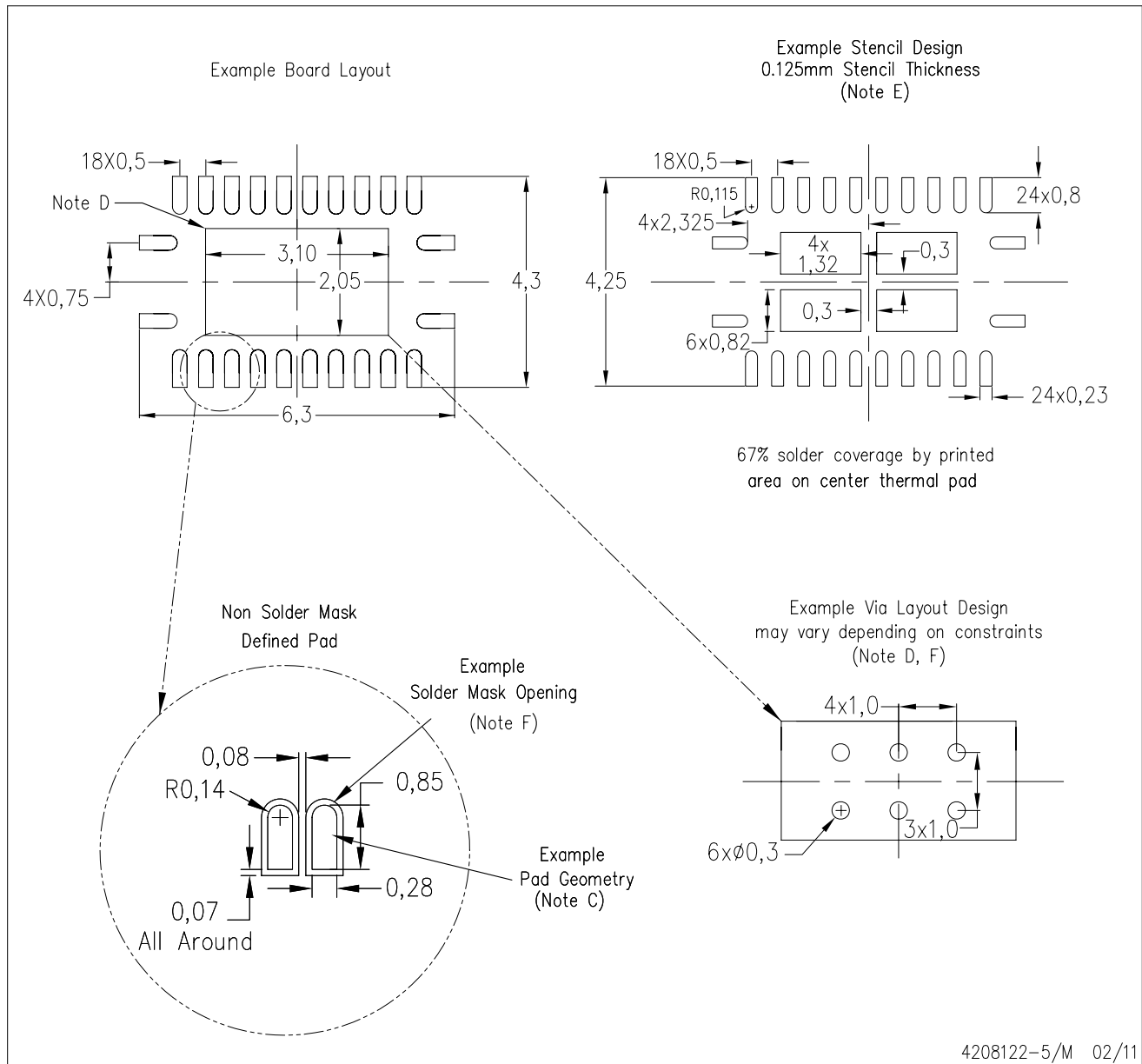
Exposed Thermal Pad Dimensions

4206353-6/M 02/11

NOTE: A. All linear dimensions are in millimeters

RGY (R-PVQFN-N24)

PLASTIC QUAD FLATPACK NO-LEAD



- NOTES:
- A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Publication IPC-7351 is recommended for alternate designs.
  - D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at [www.ti.com](http://www.ti.com) <<http://www.ti.com>>.
  - E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
  - F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)	Op Temp (°C)	Top-Side Markings (4)	Samples
BQ24170RGYR	ACTIVE	VQFN	RGY	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24170	<a href="#">Samples</a>
BQ24170RGYT	ACTIVE	VQFN	RGY	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24170	<a href="#">Samples</a>
BQ24172RGYR	ACTIVE	VQFN	RGY	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24172	<a href="#">Samples</a>
BQ24172RGYT	ACTIVE	VQFN	RGY	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24172	<a href="#">Samples</a>

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSELETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

**Green (RoHS & no Sb/Br):** TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



**TAPE AND REEL INFORMATION**

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ24170RGYR	VQFN	RGY	24	3000	330.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1
BQ24170RGYT	VQFN	RGY	24	250	180.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1
BQ24172RGYR	VQFN	RGY	24	3000	330.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1
BQ24172RGYT	VQFN	RGY	24	250	180.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1

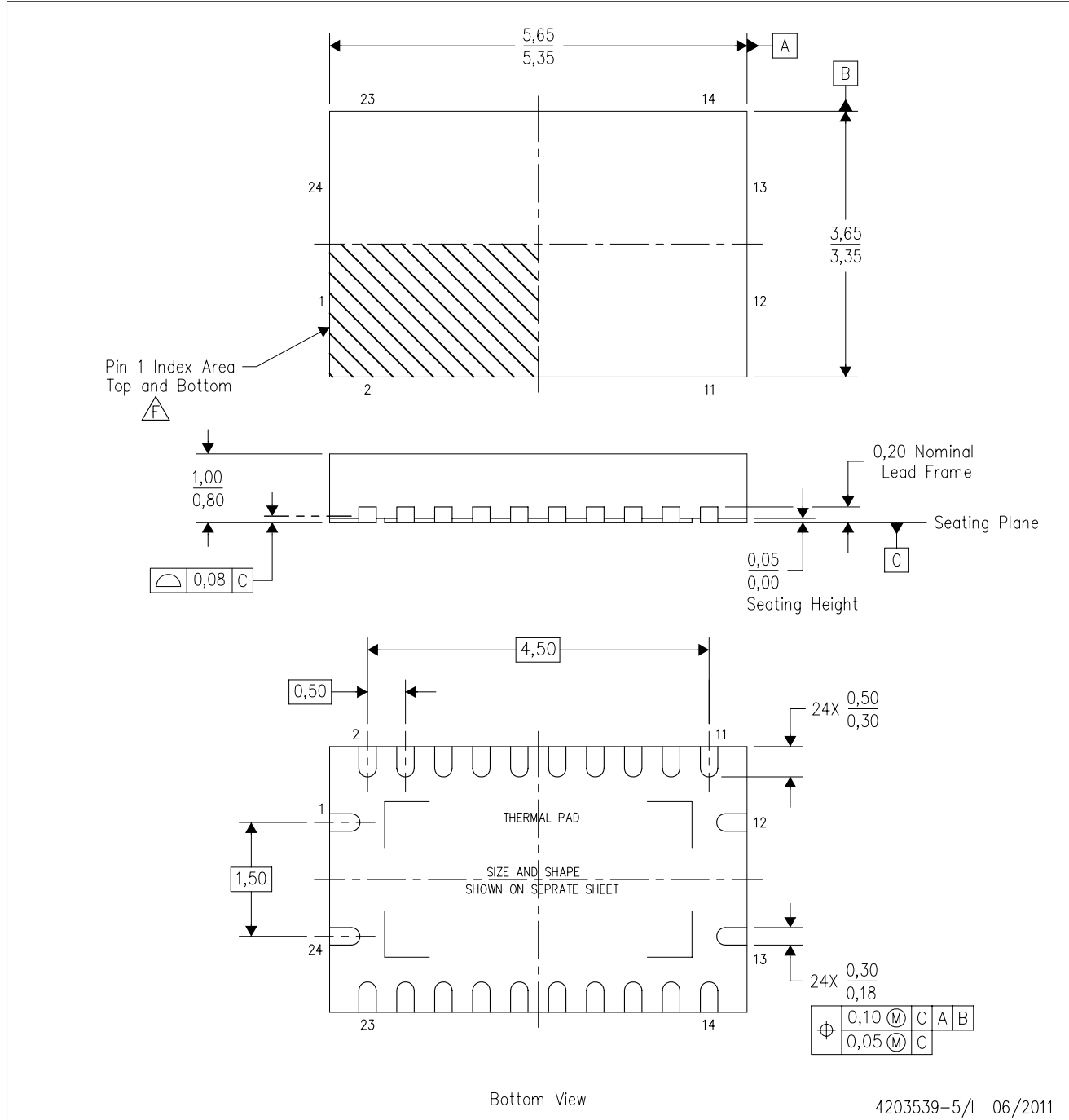
**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ24170RGYR	VQFN	RGY	24	3000	367.0	367.0	35.0
BQ24170RGYT	VQFN	RGY	24	250	210.0	185.0	35.0
BQ24172RGYR	VQFN	RGY	24	3000	367.0	367.0	35.0
BQ24172RGYT	VQFN	RGY	24	250	210.0	185.0	35.0

RGY (R-PVQFN-N24)

PLASTIC QUAD FLATPACK NO-LEAD



- NOTES:
- All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
  - This drawing is subject to change without notice.
  - QFN (Quad Flatpack No-Lead) package configuration.
  - The package thermal pad must be soldered to the board for thermal and mechanical performance.
  - See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
  - Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
  - Package complies to JEDEC MO-241 variation BA.

RGY (R-PVQFN-N24)

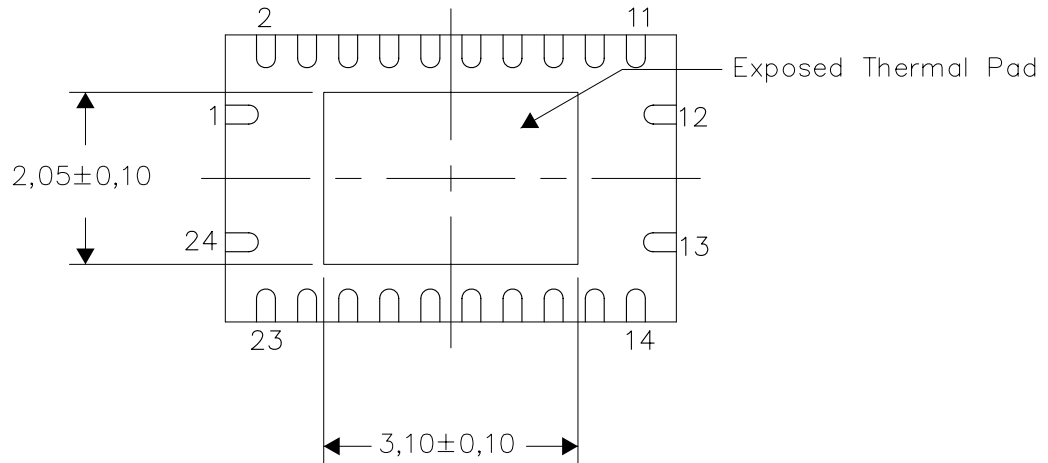
PLASTIC QUAD FLATPACK NO-LEAD

**THERMAL INFORMATION**

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at [www.ti.com](http://www.ti.com).

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

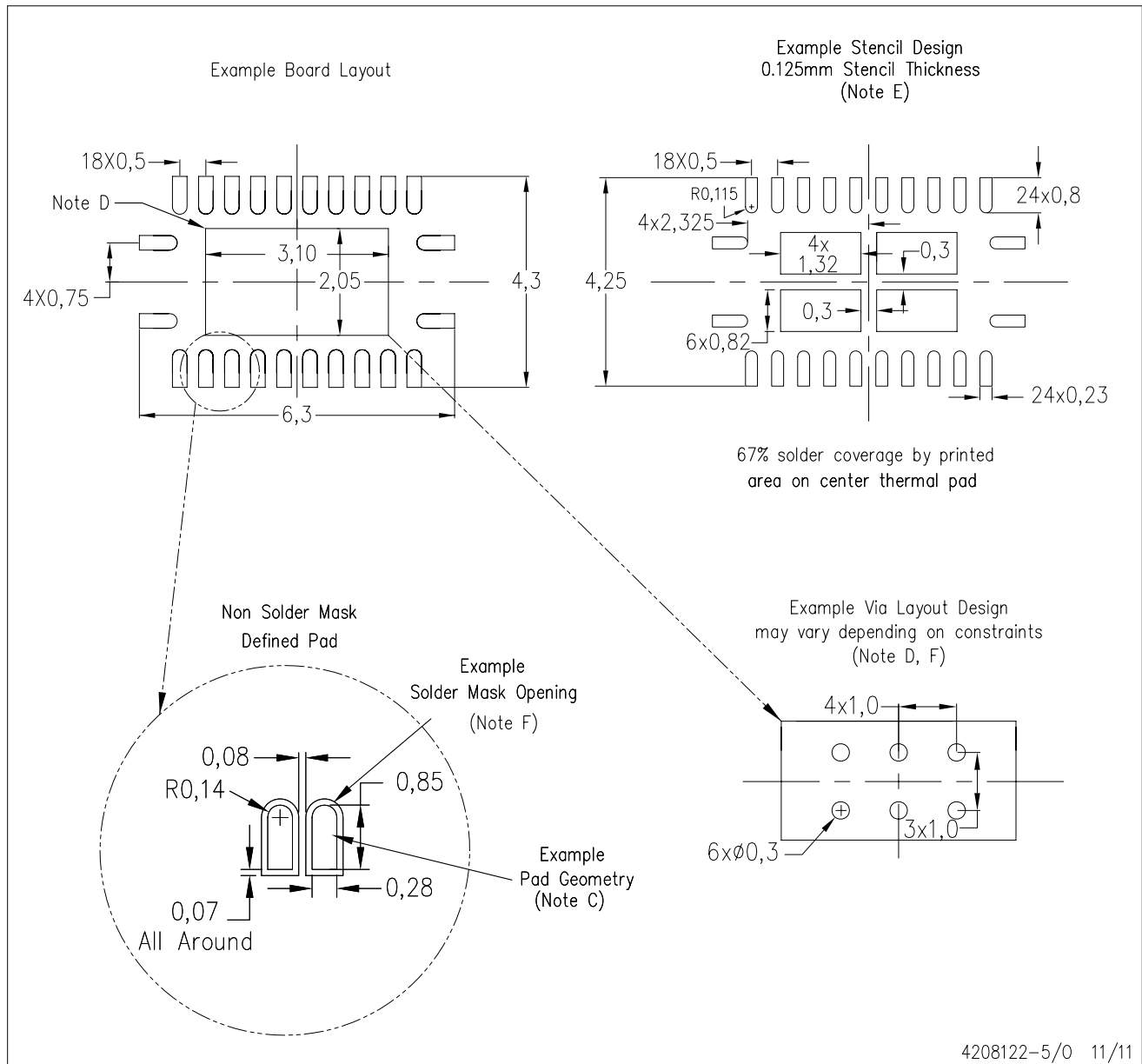
Exposed Thermal Pad Dimensions

4206353-6/0 11/11

NOTE: All linear dimensions are in millimeters

RGY (R-PVQFN-N24)

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- NOTES:
- All linear dimensions are in millimeters.
  - This drawing is subject to change without notice.
  - Publication IPC-7351 is recommended for alternate designs.
  - This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at [www.ti.com](http://www.ti.com) <<http://www.ti.com>>.
  - Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
  - Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.

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